

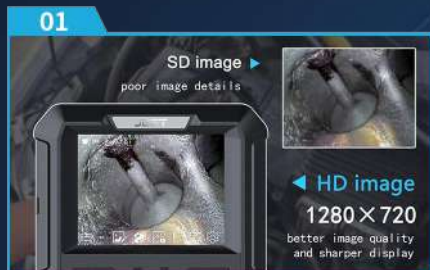
JEET



VIDEOENDOSCOP

JEET S. Serie

Calitate excelentă



1280×720 Mega HD Image



car front face design button



3.5 inches IPS
HD full-view display



Aircraft engine streamlined
design joystick



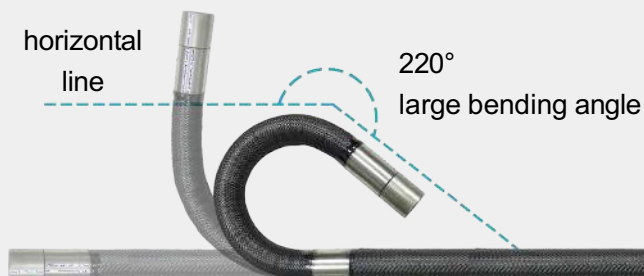
joystick
control



360°accurate
articulation

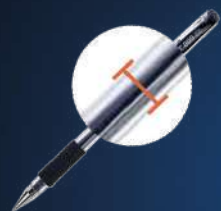
joystick-control 360°accurate articulation

horizontal
line



220°
large bending angle

220°large bending angle, ensure to
inspect every corner of detected object



Insert hole diameter
≈ pen diameter



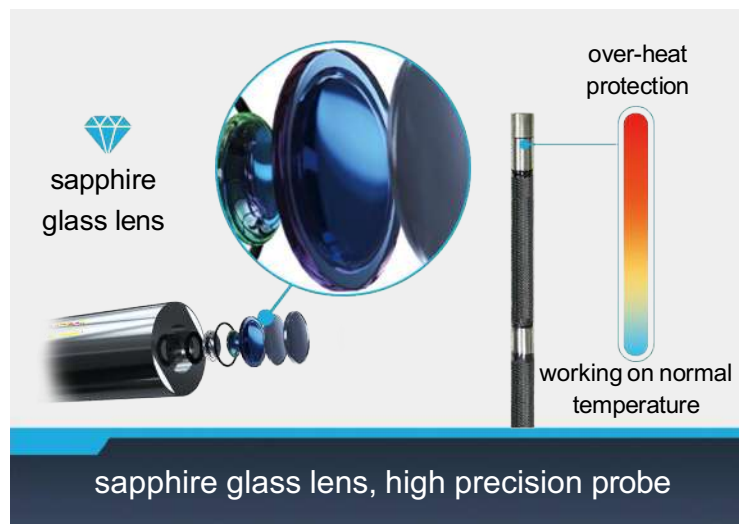
probe diameter
6mm

It can insert and inspect as long as
there are holes or gaps

super bright ceramic light
0 1 2 3 4 5



super bright ceramic light with
0-6 levels control



Sistem de tuburi	Model	S 615
	Sondă Diametru (mm)	Φ 6.0
	Tub Lungime	1,5 m
	Tub Material	aliaj tungsten
	Cameră Pixeli	1 mega pixeli
	Rezoluția imaginii	1280*720
	Grad de libertate	7~110 mm/20~150 mm
	câmp vizual	120°
	Aprinde Sursă	LED ceramică
	Iluminare	25000Lx
	Protejarea Dispozitiv de Durabilitate	protecție dispozitiv între tub și mâner
	Articulare	360° control prin joystick articulare
	Îndoire Unghi	maxim: 220°
Sistem de monitorizare	Structura	portabil
	Afișa	3.5 inci IPS vedere completă afișa
	Zoom Intrare/Ieșire	5X
	Efect de imagine	Fixare imagine, rece/cald/color
	Imagine Ajustare	imagine claritate/ contrast/gamma valoare
	Imagine/Video Format	JPEG/MP4
	Stocare fișiere	standard Card TF: 16G, Maxim: 64G
	Date Port	HDMI video ieșire, Micro USB port
	Fără fir Imagine Transmiteme	WIFI (opțional)
	Baterie	detașabilă & reîncărcabilă / baterie litiu
	Baterie Capacitate	3,7 V , 3200 mAh
	Baterie Lucru Timp	≥3H
	Baterie Încărca	DC 5V/1A
Accesorii	Exterior Materialul carcasei	aliaj rezistent la cădere
	Apă/Praf Dovidă	sondă/tub: IP67; monitor: IP65
Accesorii	Standard Configurare	valiza / videoscop/ baterie / card cititor/ TF card/încărcător/ USB cablu/ manual
	opțional	pol: 0,35-1,8 m/mini HDMI cablu/ trepied pliabil



EC - Certification of Conformity

Registration No. AGC04387200501E2

Certificate Holder Shenzhen Jeet Technology Co., Ltd.

Room 201, No.65 Gaoke Avenue, Nanyue Community, Baolong St.,
Longgang Dist., Shenzhen, China, 518116

Product Designation Videoscope

Brand Name JEET

Model / Series Models S Series

Manufacturer Shenzhen Jeet Technology Co., Ltd.

Room 201, No.65 Gaoke Avenue, Nanyue Community, Baolong St.,
Longgang Dist., Shenzhen, China, 518116

Requirement	Applied Standards	Document Evidence	Result
EMC Directive	EN 61000-6-3:2007/A1:2011/AC:2012 EN 61000-3-2:2019 EN 61000-3-3:2013/A1:2019 EN 61000-6-1: 2019	Test Report: AGC04387200501EE01	Conform



Signed by General Manager (King Zhang)

Issue Date: Jun. 03, 2020



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Note: This certificate is part of the full test report(s) and should be used in conjunction with it.



Version: 2.1

EMC Test Report

Report No.: AGC04387200501EE01

PRODUCT DESIGNATION : Videoscope
BRAND NAME : JEET
MODEL NAME : S Series
APPLICANT : Shenzhen Jeet Technology Co., Ltd.
DATE OF ISSUE : Jun. 02, 2020
STANDARD(S) : EN 61000-6-3:2007/A1:2011/AC:2012
EN61000-3-2:2019
EN61000-3-3:2013/A1:2019
EN 61000-6-1: 2019
REPORT VERSION : V1.0

Attestation of Global Compliance (Shenzhen) Co., Ltd

CAUTION:

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REPORT REVISE RECORD

Report Version	Revise Time	Issued Date	Valid Version	Notes
V1.0	/	Jun. 02, 2020	Valid	Initial release



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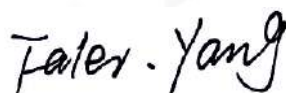
1 VERIFICATION OF CONFORMITY

Applicant	Shenzhen Jeet Technology Co., Ltd.
Address	Room 201, No.65 Gaoke Avenue, Nanyue Community, Baolong St., Longgang Dist., Shenzhen, China, 518116
Manufacturer	Shenzhen Jeet Technology Co., Ltd.
Address	Room 201, No.65 Gaoke Avenue, Nanyue Community, Baolong St., Longgang Dist., Shenzhen, China, 518116
Factory	Shenzhen Jeet Technology Co., Ltd.
Address	Room 201, No.65 Gaoke Avenue, Nanyue Community, Baolong St., Longgang Dist., Shenzhen, China, 518116
Product Designation	Videoscope
Brand Name	JEET
Test Model	S Series
Date of test	May 25, 2020 to Jun. 02, 2020
Deviation	The sample has no any deviation to the method of standard mentioned on page 1
Condition of Test Sample	Normal
Test Result	Pass

The above equipment was tested by Attestation of Global Compliance (Shenzhen) Co., Ltd. for compliance with the requirements set forth in the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

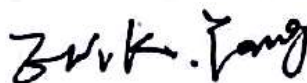
Prepared By



Faler Yang(Yang Feiyue)
Project Engineer

Jun. 02, 2020

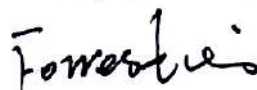
Reviewed By



Erik Yang(Yang Jianmin)
Reviewer

Jun. 02, 2020

Approved By



Forrest Lei(Lei Yonggang)
Authorized Officer

Jun. 02, 2020



2 SYSTEM DESCRIPTION

TEST MODE DESCRIPTION		
NO.	TEST MODE DESCRIPTION	WORST
1	Video Recording Supported by Adapter	V
2	Video Recording Supported by Battery	--
Note: 1. V means EMI worst mode. 2. Only worst mode data recorded in the test report.		

3 MEASUREMENT UNCERTAINTY

The uncertainty is calculated using the methods suggested in the “Guide to the Expression of Uncertainty in measurement” (GUM) published by ISO.

- Uncertainty of Conducted Emission, $U_c = \pm 3.1$ dB
- Uncertainty of Radiated Emission Below 1GHz, $U_c = \pm 4.0$ dB
- Uncertainty of Radiated Emission above 1GHz, $U_c = \pm 5.4$ dB



4 PRODUCT INFORMATION

Housing Type	Plastic and metal
EUT Input Rating	DC 5V by Adapter or DC3.7V by Battery
Adapter Model	GAT-0502000
Adapter Input Rating	AC220-240V 50/60Hz 0.45A
Adapter Output Rating	DC 5V 2000mA
Battery Model	LG18650MH1
Battery Voltage Rating	DC 3.7V 3200mAh

I/O Port Information (☒ Applicable ☐ Not Applicable)

I/O Port of EUT			
I/O Port Type	Number	Cable Description	Tested With
Micro-B	1	1.0m unshielded	1
Mini HDMI	1	--	1
TF Card	1	--	1



5 SUPPORT EQUIPMENT

Device Type	Manufacturer	Model Name	Serial No.	Data Cable	Power Cable
TF Card	SAMSUNG	--	--	--	--



6 TEST FACILITY

Site	Attestation of Global Compliance (Shenzhen) Co., Ltd
Location	1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao 'an District, Shenzhen, Guangdong, China

7 TEST EQUIPMENT LIST

TEST EQUIPMENT OF CONDUCTED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESPI	101206	Jun. 12, 2019	Jun. 11, 2020
LISN	R&S	ESH2-Z5	100086	Aug. 26, 2019	Aug. 25, 2020
Test software	R&S	ES-K1(Ver.V1.7.1)	N/A	N/A	N/A

TEST EQUIPMENT OF RADIATED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESCI	10096	Jun.12, 2019	Jun. 11, 2020
Antenna	SCHWARZBECK	VULB9168	494	Sep. 20, 2019	Sep. 19, 2021
Double-Ridge Waveguide Horn	ETS LINDGREN	3117	00034609	May. 17, 2019	May. 16, 2021
EXA Signal Analyzer	Agilent	N9010A	MY53470504	Dec. 12, 2019	Dec.11, 2020
Test software	FARA	EZ EMC (Ver.RA-03A)	N/A	N/A	N/A

TEST EQUIPMENT OF POWER HARMONICS / VOLTAGE FLUCTUATION / FLICKER TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Conditioning Unit	Schaffner	CCN1000-1	72431	Aug. 26, 2019	Aug. 25, 2020
AC Source	Schaffner	NSG1007	56825	Aug. 26, 2019	Aug. 25, 2020

TEST EQUIPMENT OF SURGE/EFT/DIPS TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
EFT Surge Generator	Schaffner	Modula 6150	34437	Aug. 26, 2019	Aug. 25, 2020



TEST EQUIPMENT OF ESD TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
ESD Simulator	EM Test	dito	P1527160053	Oct. 24, 2019	Oct. 23, 2020

TEST EQUIPMENT OF RS IMMUNITY TEST

Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Generator	R&S	E4421B	MY4335160 3	Jun. 12, 2019	Jun. 11, 2020
Power Sensor	R&S	URV5-Z4	100124	May 16, 2020	May 15, 2021
Power Meter	R&S	NRVD	8323781027	May 16, 2020	May 15, 2021
Power Amplifier	KALMUS	7100LC	04-02/17-06 -001	Jun.12, 2019	Jun.11, 2020
Power Amplifier	Milmega	AS0104-55_5 5	1004793	Jun.12, 2019	Jun.11, 2020
Double-Ridged Waveguide Horn	ETS LINDGREN	3117	00034609	May 17, 2019	May 16, 2021
Antenna	SCHWARZBECK	VULB9168	D69250	Jan. 09, 2019	Jan. 08, 2021

TEST EQUIPMENT OF CS IMMUNITY TEST

Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Power Amplifier	AR	75A250	18464	Jun. 12, 2019	Jun. 11, 2020
CDN	ZHINAN	ZN3751	15004	Sep. 09, 2019	Sep. 08, 2020
6dB attenuator	ZHINAN	E-002	N/A	Sep. 09, 2019	Sep. 08, 2020
Power Sensor	R&S	URV5-Z4	100124	May 16, 2020	May 15, 2021
Power Meter	R&S	NRVD	8323781027	May 16, 2020	May 15, 2021
Signal Generator	R&S	E4421B	MY4335160 3	Jun. 12, 2019	Jun. 11, 2020

TEST EQUIPMENT OF PFMF TEST

Description	Manufacturer	Model	Identifier	Cal. Date	Cal. Due
PFMF system	HTEC	HPFMF	161701	Aug.26, 2019	Aug.25, 2020



8 TEST SUMMARY LIST

Test item	Test Requirement	Test Method	Class/Severity	Result
CONDUCTED EMISSION	EN 61000-6-3	EN 61000-6-3	Class B	Pass
RADIATED EMISSION	EN 61000-6-3	EN 61000-6-3	Class B	Pass
Harmonic current emission	EN 61000-3-2	EN 61000-3-2	Class A	N/A
Voltage fluctuations & flicker	EN 61000-3-3	EN 61000-3-3	§5 of EN 61000-3-3	Pass
Electrostatic Discharge Immunity	EN61000-6-1	EN 61000-4-2	± 8.0 kV (Air Discharge) ± 4.0 kV (Contact Discharge) ± 4.0 kV (Indirect Discharge)	Pass
Radiated RF Electromagnetic	EN61000-6-1	EN 61000-4-3	3V/m with 80% AM. 1kHz Modulation at 80-1000MHz 3V/m with 80% AM. 1kHz Modulation at 1400-2000MHz 1V/m with 80% AM. 1kHz Modulation at 2000-2700MHz	Pass
Electrical fast transient/burst Immunity	EN61000-6-1	EN 61000-4-4	+/- 1kV for Power Supply Lines	Pass
SURGE IMMUNITY	EN61000-6-1	EN 61000-4-5	+/- 1kV (Line to Line) +/- 2kV (Line to Ground)	Pass
Immunity to Conducted Disturbances Induced by RF fields	EN61000-6-1	EN 61000-4-6	3V with 80% AM. 1 kHz Modulation	Pass
Power frequency magnetic field	EN61000-6-1	EN 61000-4-8	50/60Hz 3A/m	Pass
Voltage dips and short interruptions immunity	EN61000-6-1	EN 61000-4-11	PHASE ANGLE 0 degrees	Pass

Note : N/A means not applicable.



9 EN 61000-6-3 LINE CONDUCTED EMISSION TEST

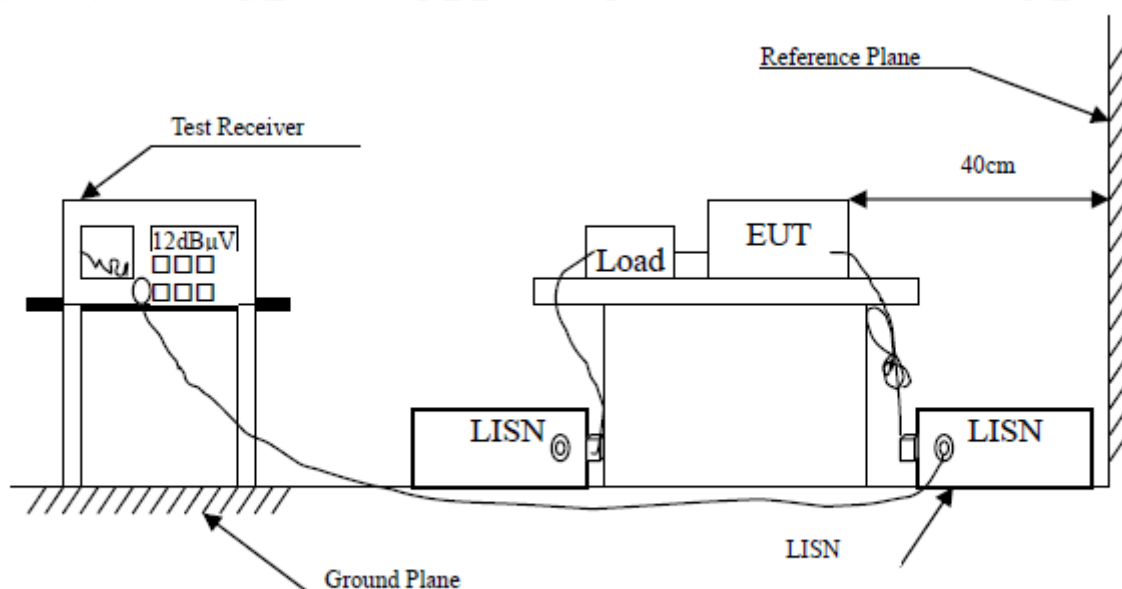
9.1 LIMITS OF LINE CONDUCTED EMISSION TEST

Frequency	Maximum RF Line Voltage	
	Q.P.(dBuV)	Average(dBuV)
150kHz-500kHz	66-56	56-46
500kHz-5MHz	56	46
5MHz-30MHz	60	50

Note:

1. The lower limit shall apply at the transition frequency.
2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz.

9.2 BLOCK DIAGRAM OF TEST SETUP



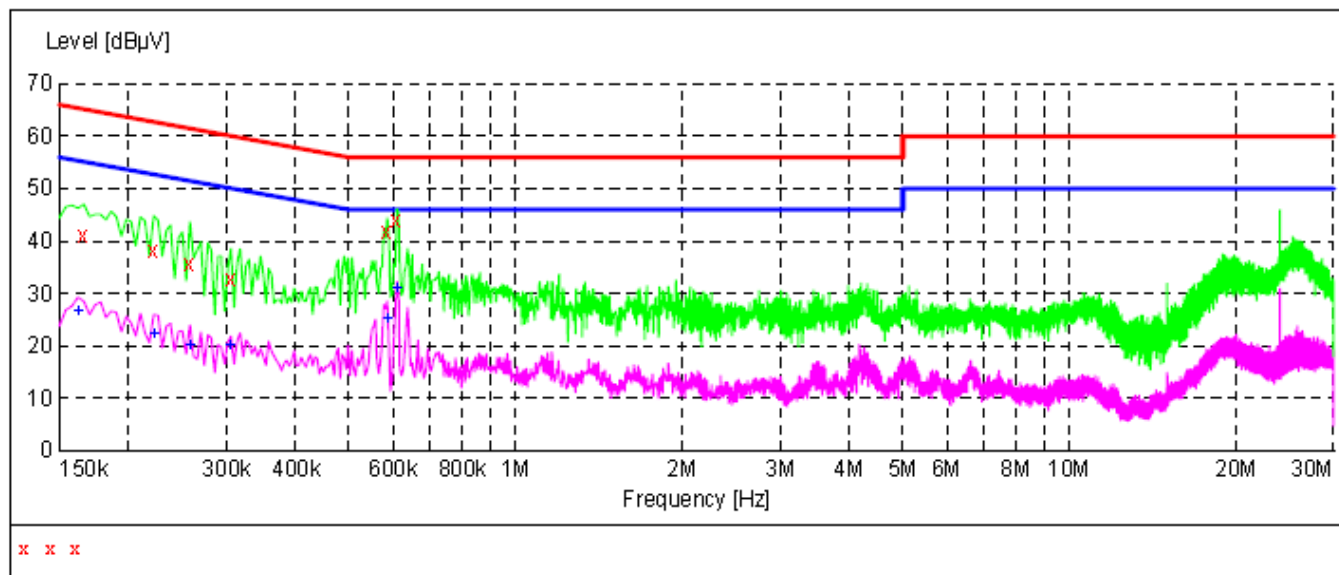
9.3 PROCEDURE OF LINE CONDUCTED EMISSION TEST

- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN61000-6-3 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 10cm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN61000-6-3.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN61000-6-3.
- (4) The EUT received DC 5V power from adapter which received AC230V 50Hz power through a Line Impedance Stabilization Network (LISN).
- (5) All support equipments received power from a second LISN supplying power of AC 230V/50Hz, if any.
- (6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- (7) Analyzer / Receiver scanned from 150 kHz to 30 MHz for emissions in each of the test modes.
- (8) During the above scans, the emissions were maximized by cable manipulation.
- (9) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions.
- (10) Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less -2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.



9.4 TEST RESULT OF LINE CONDUCTED EMISSION TEST

LINE CONDUCTED EMISSION TEST-L



MEASUREMENT RESULT:

Frequency MHz	Level dBμV	Transd dB	Limit dBμV	Margin dB	Detector	Line
0.166000	41.00	10.3	65	24.2	QP	L1
0.222000	38.00	10.3	63	24.7	QP	L1
0.258000	35.80	10.3	62	25.7	QP	L1
0.306000	32.80	10.3	60	27.3	QP	L1
0.586000	41.90	10.3	56	14.1	QP	L1
0.610000	44.10	10.3	56	11.9	QP	L1

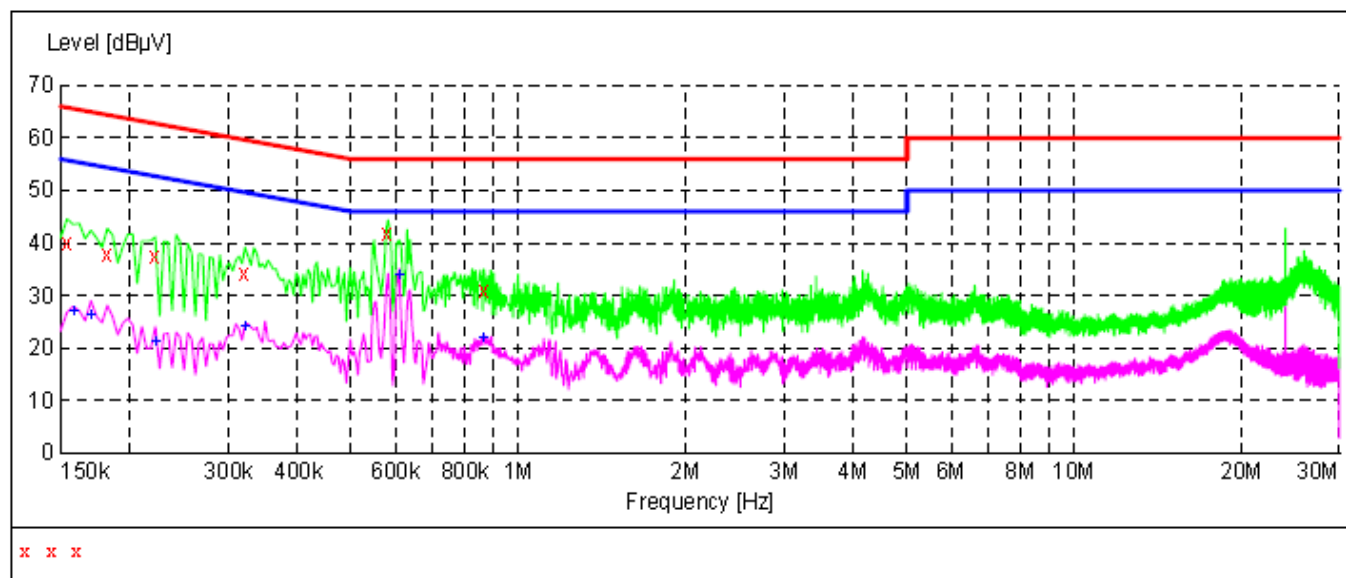
MEASUREMENT RESULT:

Frequency MHz	Level dBμV	Transd dB	Limit dBμV	Margin dB	Detector	Line
0.162000	26.60	10.3	55	28.8	AV	L1
0.222000	22.10	10.3	53	30.6	AV	L1
0.258000	20.10	10.3	52	31.4	AV	L1
0.306000	20.00	10.3	50	30.1	AV	L1
0.586000	25.00	10.3	46	21.0	AV	L1
0.610000	31.00	10.3	46	15.0	AV	L1

RESULT: PASS



LINE CONDUCTED EMISSION TEST-N



MEASUREMENT RESULT:

Frequency MHz	Level dBμV	Transd dB	Limit dBμV	Margin dB	Detector	Line
0.154000	40.00	10.3	66	25.8	QP	N
0.182000	37.70	10.3	64	26.7	QP	N
0.222000	37.50	10.3	63	25.2	QP	N
0.322000	34.00	10.3	60	25.7	QP	N
0.582000	41.70	10.3	56	14.3	QP	N
0.866000	30.80	10.3	56	25.2	QP	N

MEASUREMENT RESULT:

Frequency MHz	Level dBμV	Transd dB	Limit dBμV	Margin dB	Detector	Line
0.158000	26.90	10.3	56	28.7	AV	N
0.170000	26.10	10.3	55	28.9	AV	N
0.222000	21.00	10.3	53	31.7	AV	N
0.322000	23.90	10.3	50	25.8	AV	N
0.610000	33.90	10.3	46	12.1	AV	N
0.866000	21.90	10.3	46	24.1	AV	N

RESULT: PASS



10 EN 61000-6-3 RADIATED EMISSION TEST

10.1 LIMITS OF RADIATED DISTURBANCES

AT 10M DISTANCES

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m Q.P.)
30-230	10	30.00
230-1000	10	37.00

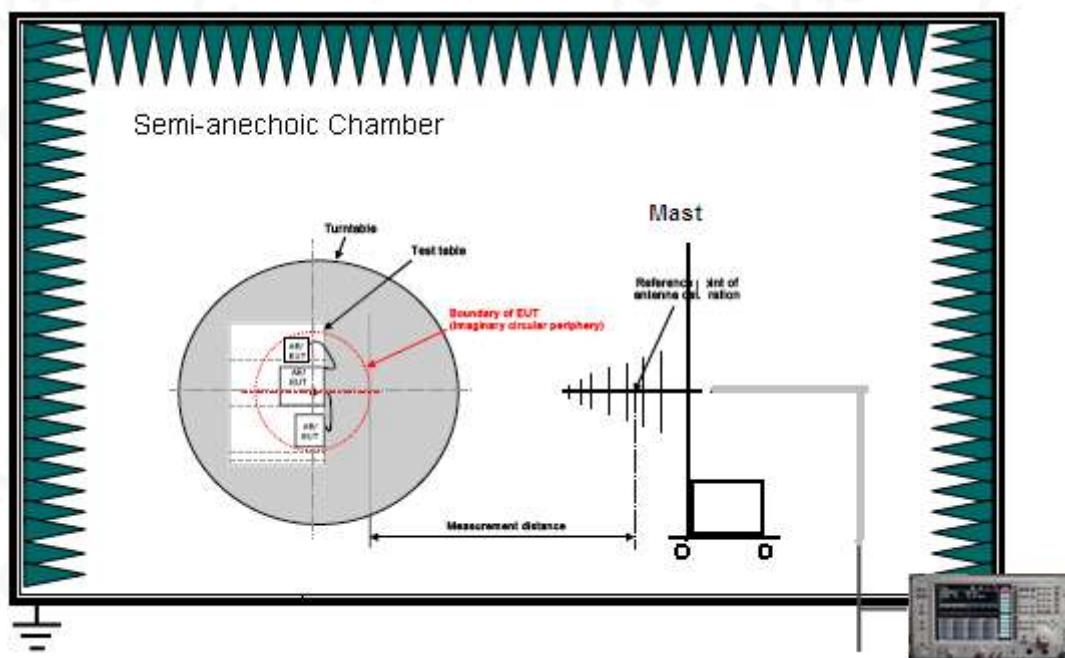
AT 3M DISTANCES

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m Q.P.)
30-230	3	40.00
230-1000	3	47.00

Note: The lower limit shall apply at the transition frequency.

10.2 BLOCK DIAGRAM OF TEST SETUP

System Diagram of Connections between EUT and Simulators



10.3 PROCEDURE OF RADIATED EMISSION TEST

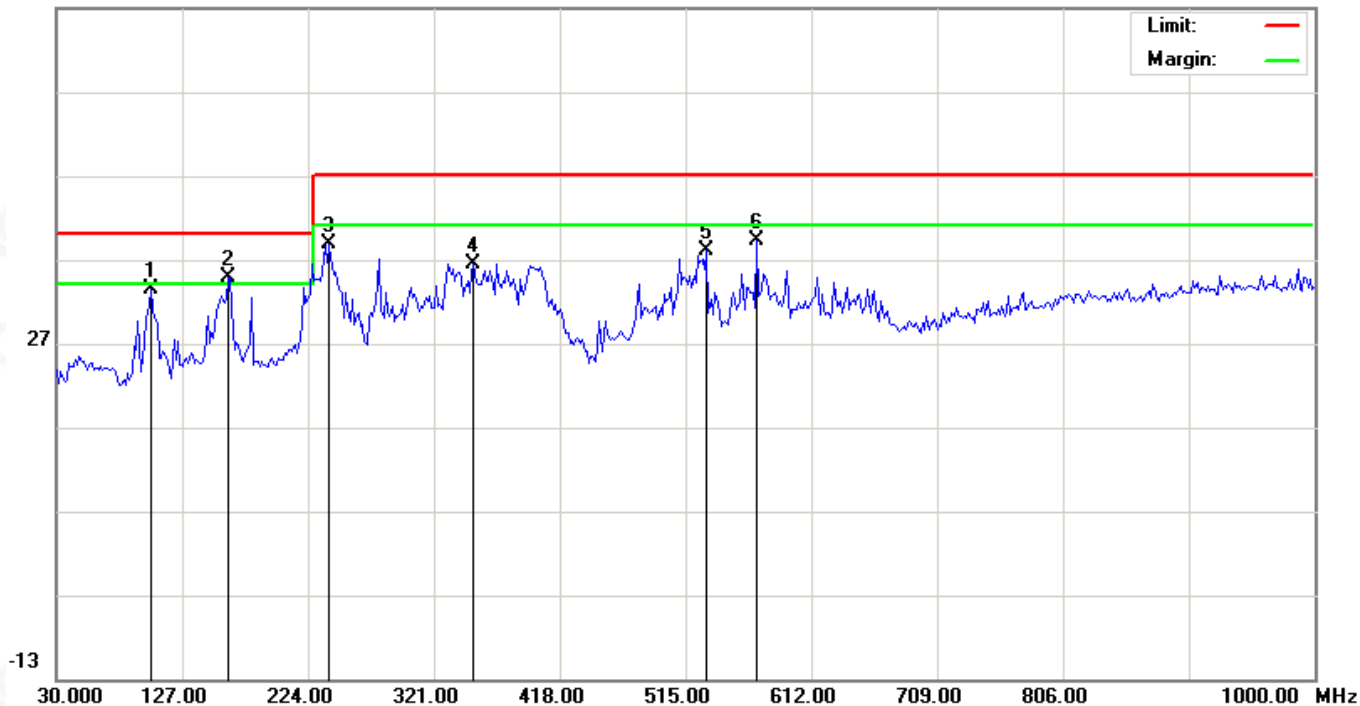
- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 61000-6-3 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 10cm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN 61000-6-3.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN 61000-6-3.
- (4) The EUT received DC 5V power from adapter which received AC 230V/50Hz power from socket on the turntable.
- (5) The antenna was placed at 3 meter away from the EUT as stated in EN 61000-6-3. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- (6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- (7) The test mode(s) were scanned during the test.
- (8) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and Q.P./Peak reading is presented.



10.4 TEST RESULT OF RADIATED EMISSION TEST

Radiated Emission Test at 3m Distance-Horizontal

66.9 dBuV/m

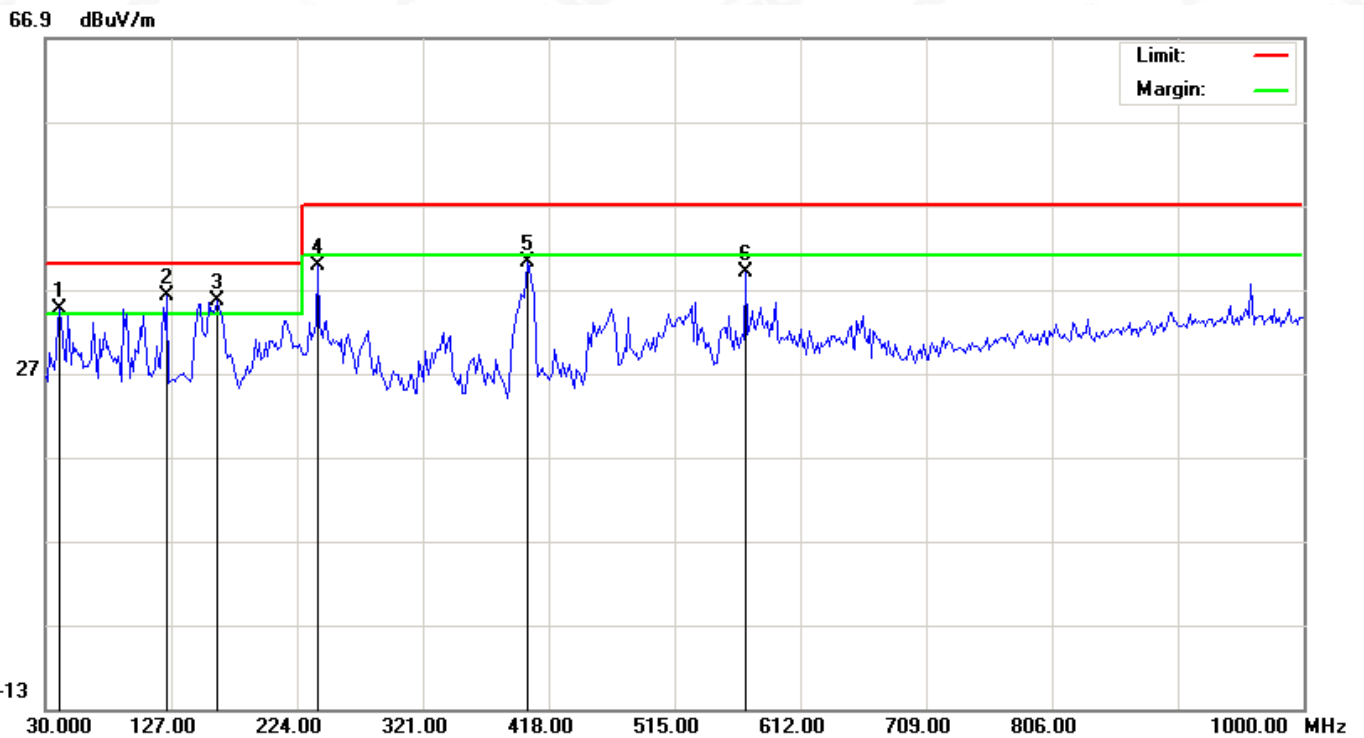


No.	Mk	Freq.	Reading	Factor	Measurement	Limit	Over	Detector	Antenna Height	Table Degree	Comment
		MHz	dBuV	dB/m	dBuV/m	dBuV/m	dB		cm	degree	
1		102.7500	17.10	16.28	33.38	40.00	-6.62	peak			
2	*	162.5666	15.90	18.93	34.83	40.00	-5.17	peak			
3		240.1666	20.15	18.66	38.81	47.00	-8.19	peak			
4		351.7167	15.21	21.29	36.50	47.00	-10.50	peak			
5		531.1666	12.38	25.60	37.98	47.00	-9.02	peak			
6		569.9666	12.80	26.36	39.16	47.00	-7.84	peak			

RESULT: PASS



Radiated Emission Test at 3m Distance-Vertical

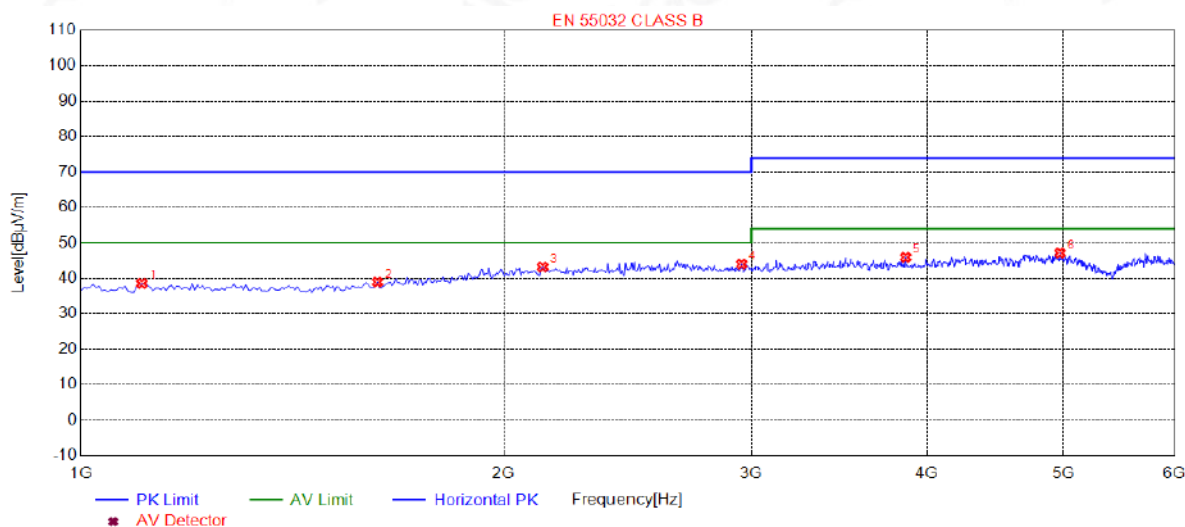


No.	Mk	Freq.	Reading	Factor	Measurement	Limit	Over	Detector	Antenna Height	Table Degree	Comment
		MHz	dBuV	dB/m	dBuV/m	dBuV/m	dB		cm	degree	
1	!	41.3166	14.65	20.04	34.69	40.00	-5.31	peak			
2	*	123.7667	17.95	18.21	36.16	40.00	-3.84	peak			
3	!	162.5665	16.58	18.93	35.51	40.00	-4.49	peak			
4		240.1665	21.13	18.66	39.79	47.00	-7.21	peak			
5		401.8333	17.26	23.02	40.28	47.00	-6.72	peak			
6		569.9665	12.65	26.36	39.01	47.00	-7.99	peak			

RESULT: PASS



Radiated Emission Test at 3m Distance Above 1G-Horizontal

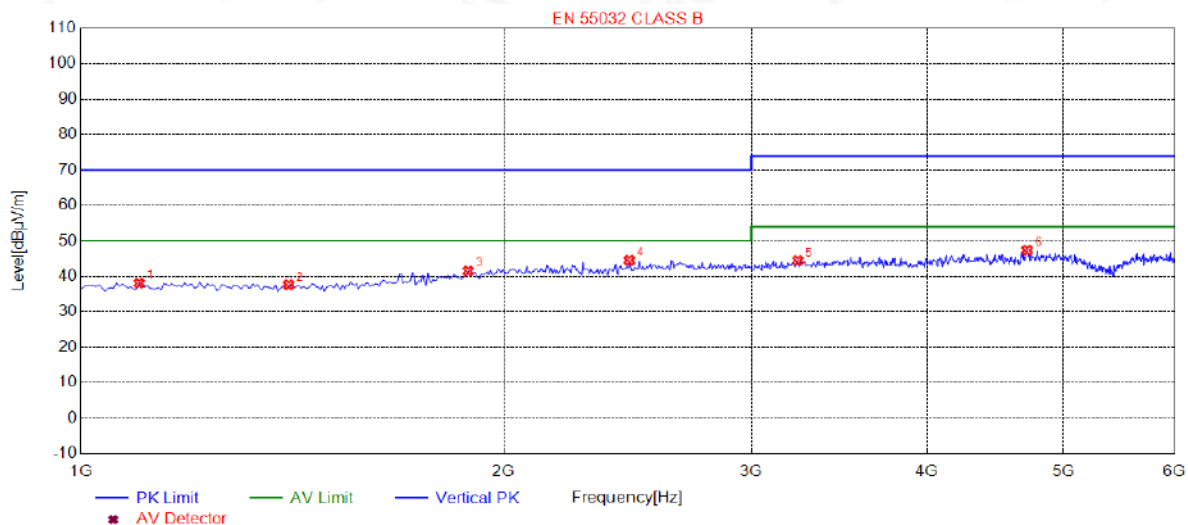


NO.	Freq. [MHz]	Level [dBμV/m]	Factor [dB]	Limit [dBμV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity
1	1105.10	38.58	-16.74	70.00	31.42	100	296	Horizontal
2	1625.62	38.97	-15.80	70.00	31.03	100	3	Horizontal
3	2131.13	43.18	-11.27	70.00	26.82	100	220	Horizontal
4	2951.95	44.01	-9.37	70.00	25.99	100	224	Horizontal
5	3862.86	45.95	-6.80	74.00	28.05	100	1	Horizontal
6	4973.97	47.17	-4.74	74.00	26.83	100	213	Horizontal

RESULT: PASS



Radiated Emission Test at 3m Distance Above 1G –Vertical



NO.	Freq. [MHz]	Level [dBμV/m]	Factor [dB]	Limit [dBμV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity
1	1100.10	38.07	-16.74	70.00	31.93	100	299	Vertical
2	1405.40	37.63	-17.04	70.00	32.37	100	27	Vertical
3	1885.88	41.50	-13.03	70.00	28.50	100	222	Vertical
4	2456.45	44.51	-9.90	70.00	25.49	100	186	Vertical
5	3237.23	44.45	-8.51	74.00	29.55	100	259	Vertical
6	4713.71	47.40	-4.99	74.00	26.60	100	330	Vertical

RESULT: PASS

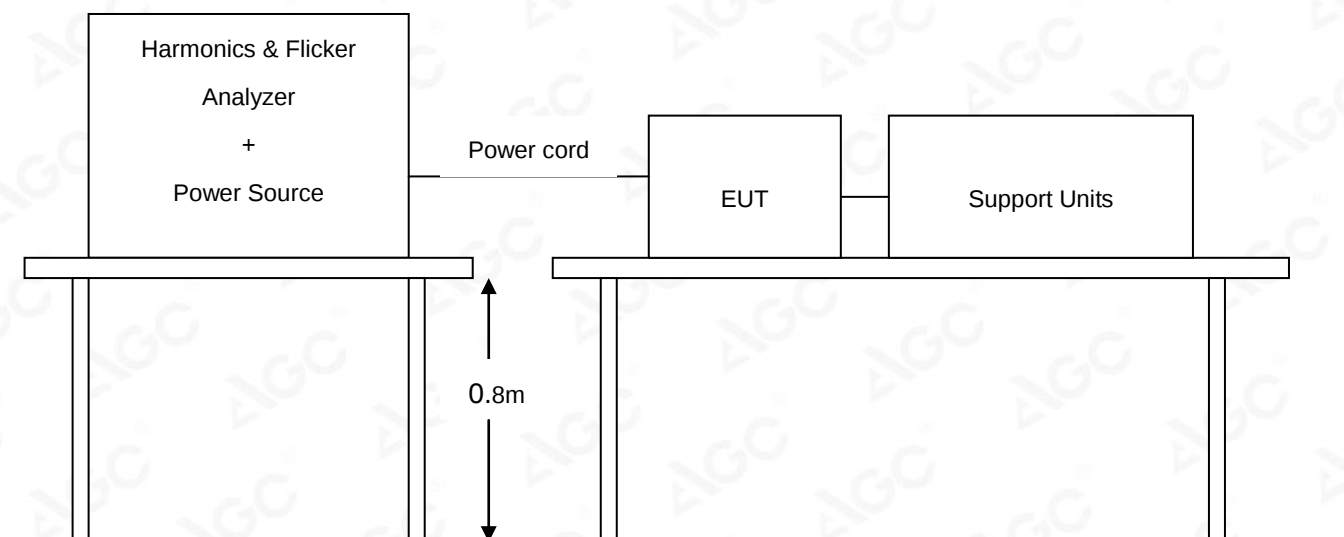


11 EN 61000-3-2 POWER HARMONICS TEST

POWER HARMONICS MEASUREMENT

Port	AC mains
Basic Standard	EN 61000-3-2
Limits	☒ CLASS A ; ☐ CLASS B ; ☐ CLASS C ; ☐ CLASS D
Temperature	25°C
Humidity	55%

11.1 BLOCK DIAGRAM OF TEST SETUP



11.2 RESULT

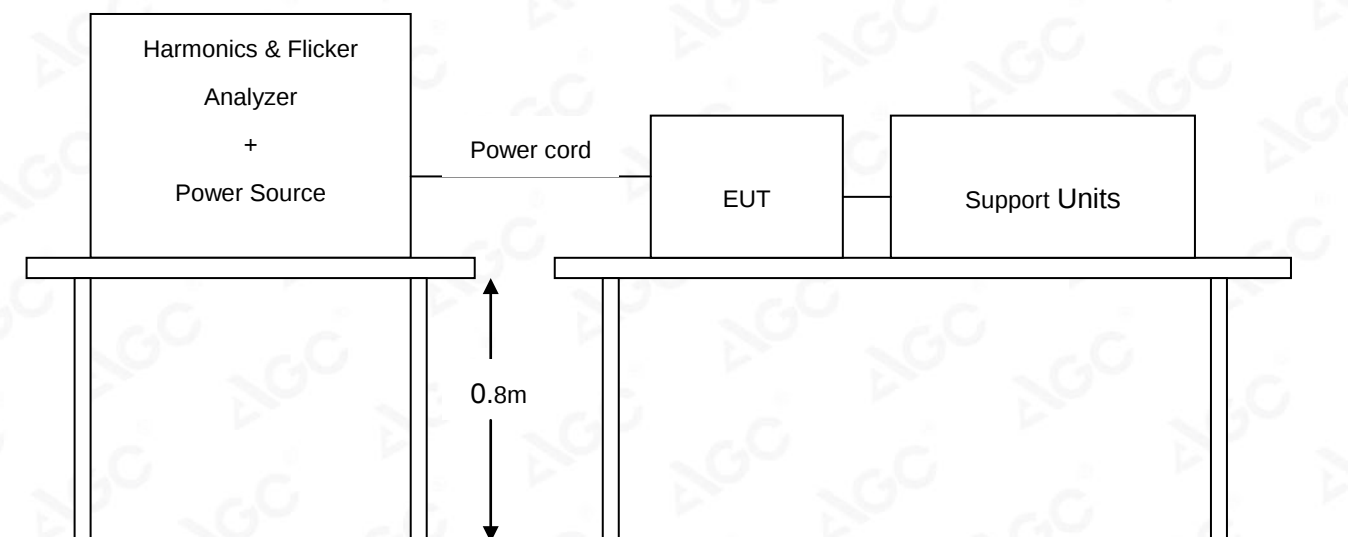
Note: Owing to the power of EUT is less than 75W, so test is not applicable.

12 EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST

VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port	AC mains
Basic Standard	EN 61000-3-3
Limits	§5 of EN 61000-3-3
Temperature	25°C
Humidity	55%

12.1 BLOCK DIAGRAM OF TEST SETUP



12.2 RESULT

Flicker Test Summary per EN/IEC61000-3-3 (Run time)

EUT: S Series

Tested by: Faler

Test category: All parameters (European limits)

Test Margin: 100

Test date: 29/05/2019

Start time: 16:50:52

End time: 17:01:14

Test duration (min): 10

Data file name: F-001173.cts_data

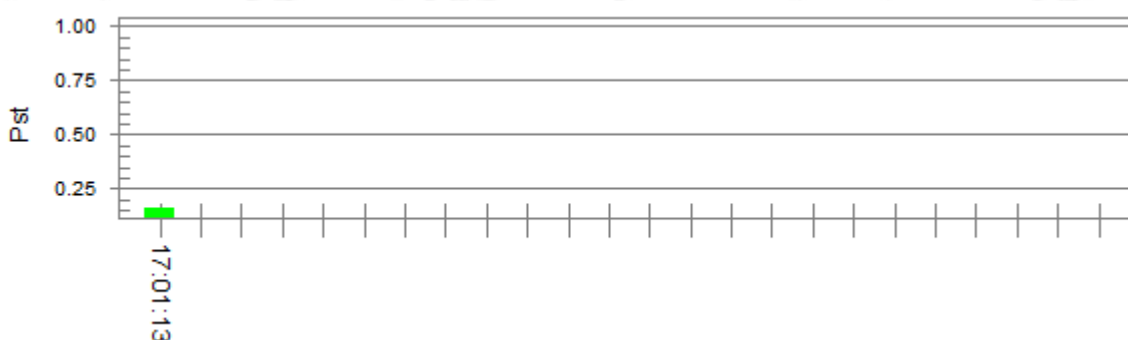
Customer: Shenzhen Jeet Technology Co., Ltd.

Test Result: Pass

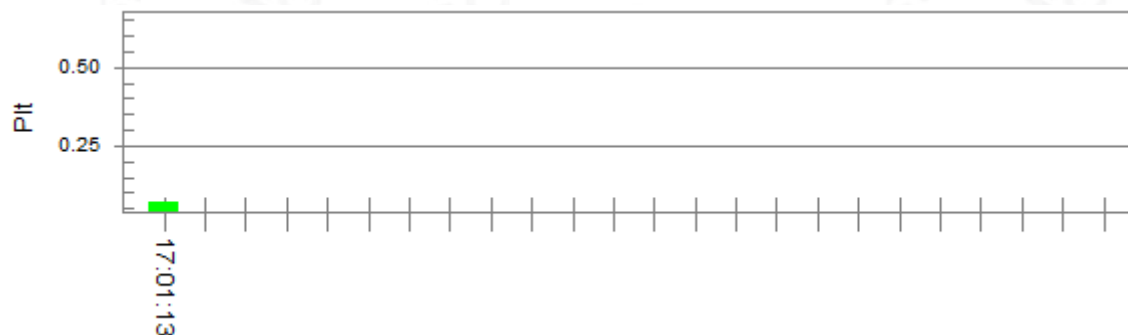
Status: Test Completed

Pst and limit line

European Limits



Plt and limit line



Parameter values recorded during the test:

Vrms at the end of test (Volt): 230.73

Highest dt (%):	0.00	Test limit (%):	3.30	Pass
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Time(mS) > dt:	0.00	Test limit (mS):	500.0	Pass
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Highest dc (%):	0.00	Test limit (%):	3.30	Pass
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Highest dmax (%):	0.00	Test limit (%):	4.00	Pass
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Highest Pst (10 min. period):	0.160	Test limit:	1.000	Pass
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Highest Plt (2 hr. period):	0.070	Test limit:	0.650	Pass
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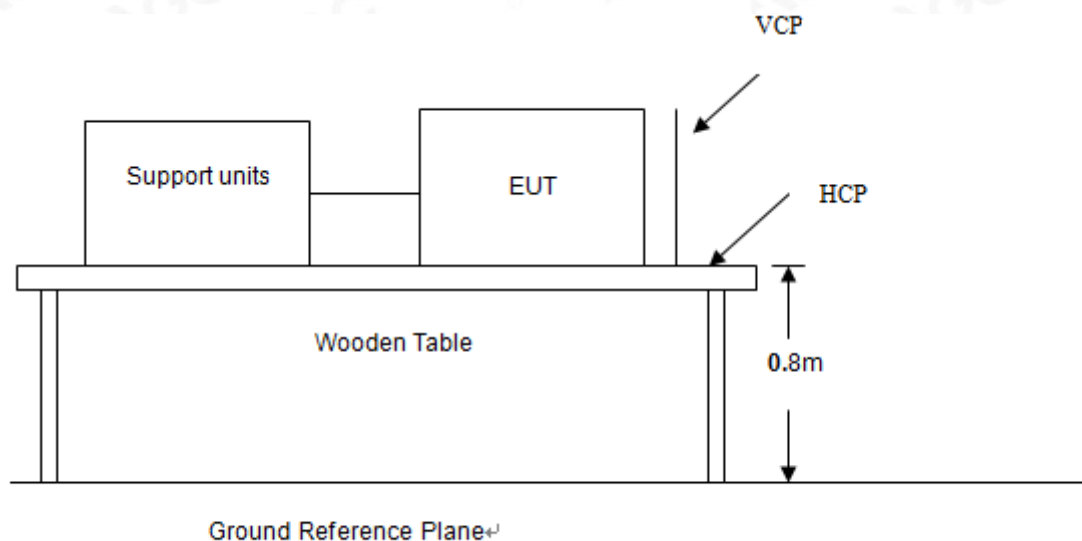
13 EN 61000-4-2 ESD IMMUNITY TEST

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port	Enclosure
Basic Standard	EN 61000-4-2
Test Level	±8.0 kV (Air Discharge) ±4.0 kV (Contact Discharge) ±4.0 kV (Indirect Discharge)
Standard require	B
Temperature	23.3°C
Humidity	57.3%

13.1 BLOCK DIAGRAM OF TEST SETUP

(The 470 k ohm resistors are installed per standard requirement)



13.2 TEST PROCEDURE

The EUT was located 0.1 m minimum from all side of the HCP.

The support units were located 1 m minimum away from the EUT.

EUT worked with resistance load, and make sure EUT worked normally.

Active the communication function if the EUT with such port(s).

As per the requirement of EN 61000-4-2; applying direct contact discharge at the sides other than front of EUT at minimum 20 discharges (10 positive and 10 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.

Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.

The application of ESD to the contact of open connectors is not required.

Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

Note: As per the A2 to EN 61000-4-2, a bleed resistor cable is connected between the EUT and HCP during the test.

The electrostatic discharges were applied as follows:

Voltage	Coupling	Test Performance	Result
±4kV	Contact Discharge	No function loss	A
±4kV	Indirect Discharge HCP (Front)	No function loss	A
±4kV	Indirect Discharge HCP (Back)	No function loss	A
±4kV	Indirect Discharge HCP (Left)	No function loss	A
±4kV	Indirect Discharge HCP (Right)	No function loss	A
±4kV	Indirect Discharge VCP (Front)	No function loss	A
±4kV	Indirect Discharge VCP (Back)	No function loss	A
±4kV	Indirect Discharge VCP (Left)	No function loss	A
±4kV	Indirect Discharge VCP (Right)	No function loss	A
±8kV	Air Discharge	No function loss	A



13.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS**

☐ **FAIL**

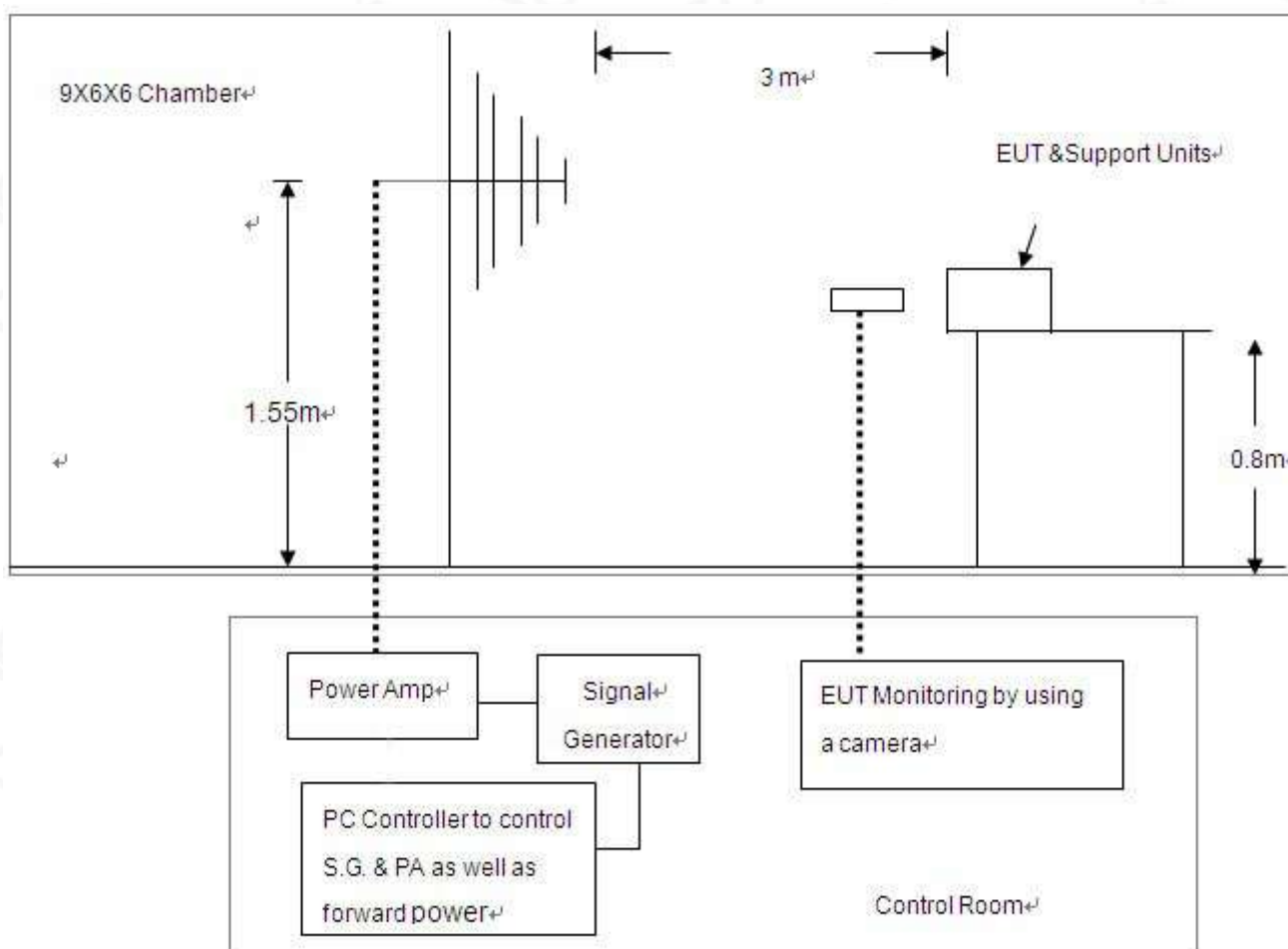


14 EN 61000-4-3 RS IMMUNITY TEST

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port	Enclosure
Basic Standard	EN 61000-4-3
Test Level	3V/m with 80% AM. 1kHz Modulation at 80-1000MHz 3V/m with 80% AM. 1kHz Modulation at 1400-2000MHz 1V/m with 80% AM. 1kHz Modulation at 2000-2700MHz
Standard require	A
Temperature	23.4°C
Humidity	58.0%

14.1 BLOCK DIAGRAM OF TEST SETUP



14.2 TEST PROCEDURE

The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per EN 61000-4-3.

EUT worked with resistance load, and make sure EUT worked normally.

Setting the testing parameters of RS test software per EN 61000-4-3.

From the result of pre-test in step 5, choose the worst side of EUT for final test from 80 MHz to 1000 MHz and 1400MHz to 2700MHz at 1% steps.

Recording the test result in following table.

Test level: 3V/m

Steps: 1 % of fundamental

Dwell Time: 1 sec

Range (MHz)	Field	Modulation	Polarity	Position	Result
1400-6000	3V/m	AM	H	Front	A
1400-6000	3V/m	AM	H	Left	A
1400-6000	3V/m	AM	H	Back	A
1400-6000	3V/m	AM	H	Right	A
1400-6000	3V/m	AM	V	Front	A
1400-6000	3V/m	AM	V	Left	A
1400-6000	3V/m	AM	V	Back	A
1400-6000	3V/m	AM	V	Right	A



14.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ PASS ☐ FAIL
--

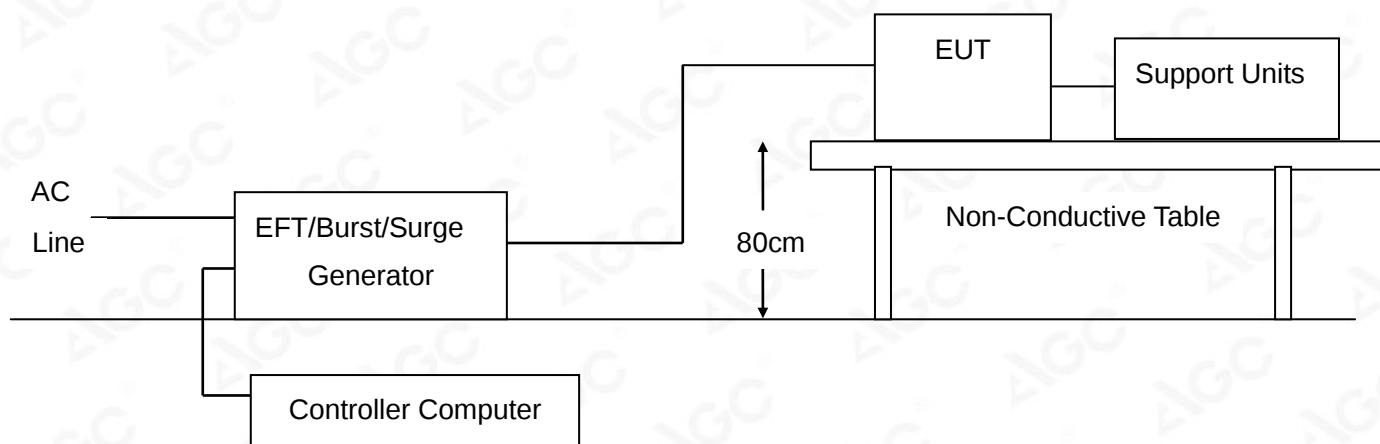


15 EN 61000-4-4 EFT IMMUNITY TEST

ELECTRICAL FAST TRANSIENTS/BURST IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-4
Test Level	+/-1kV for Power Supply Lines
Standard require	B
Temperature	22.8°C
Humidity	57.0%

15.1 BLOCK DIAGRAM OF TEST SETUP



15.2 TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8m away from ground reference plane.
A 1.0 meter long power cord was attached to EUT during the test.
The length of communication cable between communication port and clamp was keeping within 1 meter.
EUT worked with resistance load, and make sure EUT worked normally.
Related peripherals work during the test.
Recording the test result as shown in following table.

Test conditions:

Impulse Frequency: 5 kHz

Tr/Th: 5/50ns

Burst Duration: 15ms

Burst Period: 300ms

Inject Line	Voltage kV	Inject Method	Result
L ₁ +N	+/- 1	Direct	A

15.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

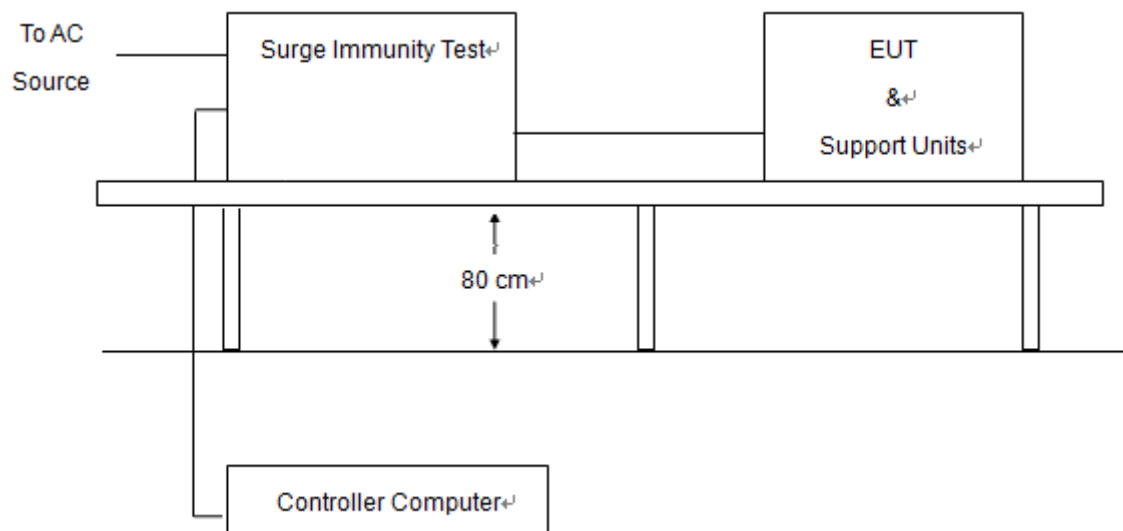
☒ **PASS**
☐ **FAIL**


16 EN 61000-4-5 SURGE IMMUNITY TEST

SURGE IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-5
Requirements	+/- 1 kV (Line to Line) +/- 2kV (Line to Ground)
Standard require	B
Temperature	22.8°C
Humidity	57.0%

16.1 BLOCK DIAGRAM OF TEST SETUP



16.2 TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8 m away from ground floor.

EUT worked with resistance load, and make sure EUT worked normally.

Recording the test result as shown in following table.

Test conditions:

Voltage Waveform	1.2/50 μ s
Current Waveform	8/20 μ s
Polarity	Positive/Negative
Phase Angle	0°, 90°, 180°, 270°
Number of Test	5
Time of Test	1 per minute

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result
L ₁ -N	1	Positive	Capacitive	A
L ₁ -N	1	Negative	Capacitive	A

16.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

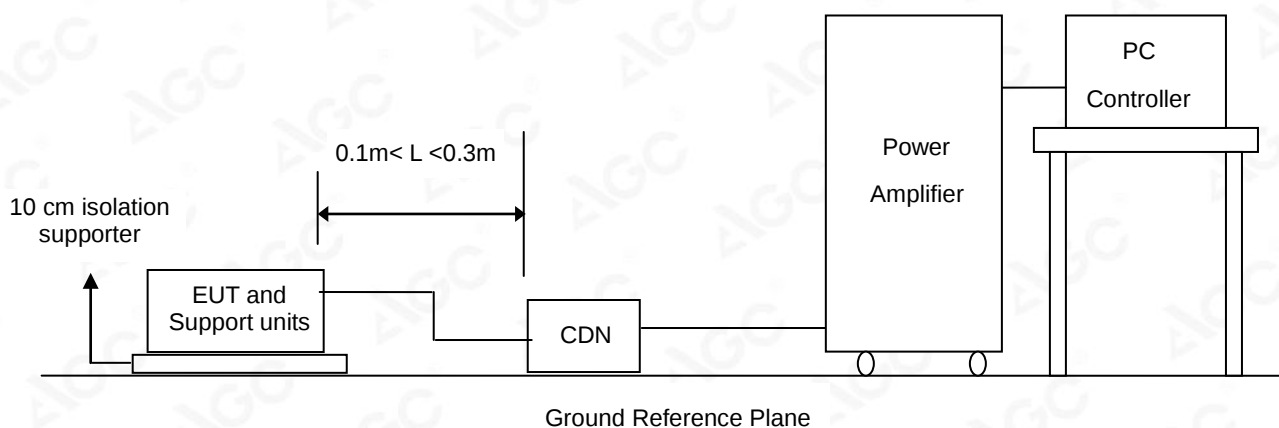
☒ **PASS**
☐ **FAIL**


17 EN 61000-4-6 CS IMMUNITY TEST

EN 61000-4-6 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELD

Port	On Power Supply Lines
Basic Standard	EN 61000-4-6
Requirements	3V with 80% AM. 1 kHz Modulation
Standard require	A
Temperature	23.7°C
Humidity	56.9%

17.1 BLOCK DIAGRAM OF TEST SETUP



17.2 TEST PROCEDURE

The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Setting the testing parameters of CS test software per EN 61000-4-6.

Recording the test result in following table.

Test conditions:

Frequency Range	0.15MHz-80MHz
Frequency Step	1% of fundamental
Dwell Time	1 sec

Range (MHz)	Strength	Modulation	Result
0.15-80	3V	AM	A

17.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

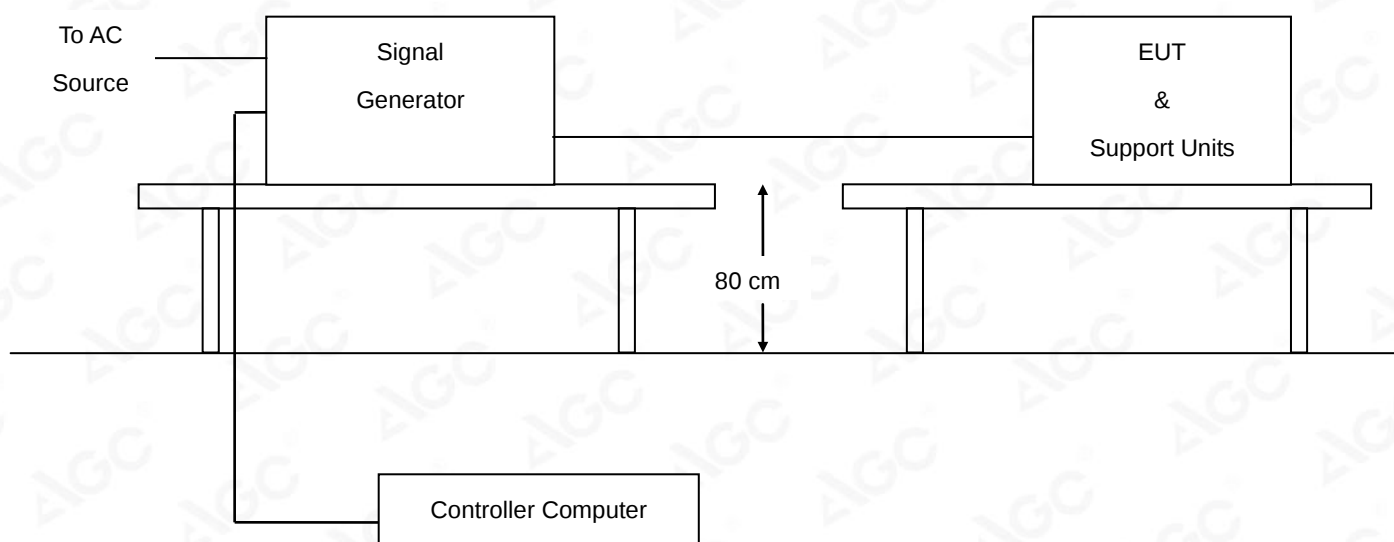
☒ **PASS**
☐ **FAIL**


18 EN 61000-4-8 PFMF TEST

POWER FREQUENCY MAGNETIC FIELDS IMMUNITY TEST

Port	Enclosure
Basic Standard	EN 61000-4-8
Requirements	50/60 Hz, 3A/m
Standard require	A
Temperature	25°C
Humidity	55%

18.1 BLOCK DIAGRAM OF TEST SETUP



18.2 TEST PROCEDURE

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions (1m × 1m). The induction coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

Test Conditions:

Frequency	Polarity	Level	Test Performance	Performance Result
50 Hz	X	3 A/m	No function loss	A
50 Hz	Y	3 A/m	No function loss	A
50 Hz	Z	3 A/m	No function loss	A

18.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

☒ **PASS**
☐ **FAIL**

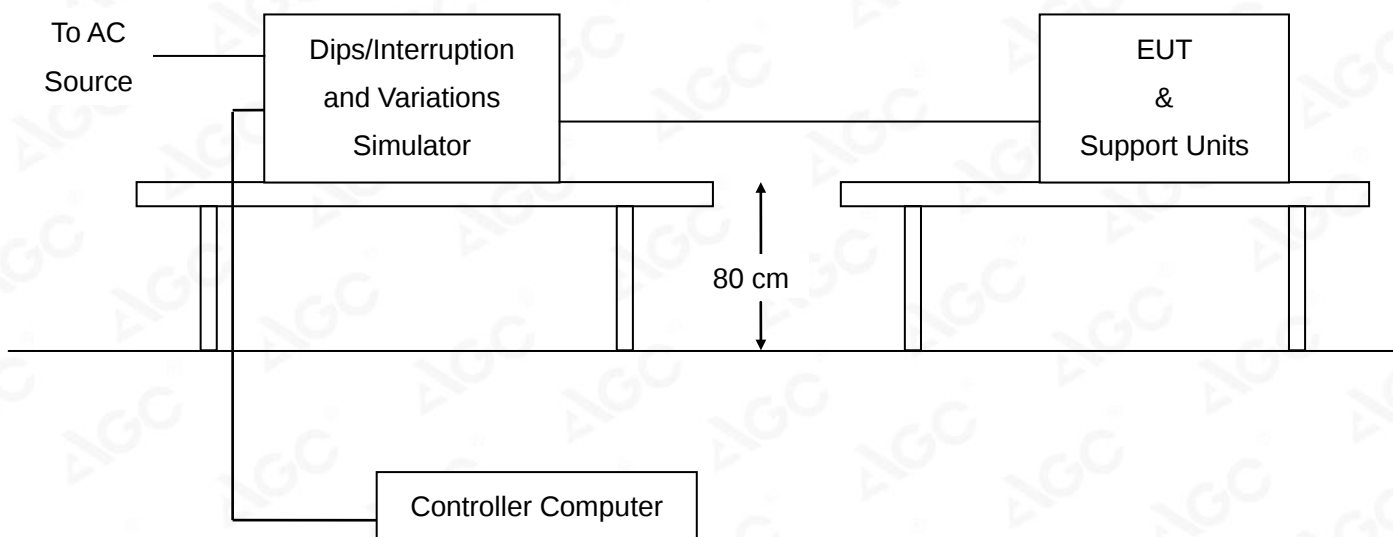

19 EN 61000-4-11 VOLTAGE DIPS TEST

VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-11
Requirements	PHASE ANGLE 0 degrees
Test Interval	Min. 10 sec.
Temperature	22.8°C
Humidity	57.0%

Voltage Dips	Test Level % U_T	Reduction (%)	Duration (periods)	Performance Criteria
	0	100	0.5	B
	0	100	1	B
	70	30	25	C
Voltage Interruption	Test Level % U_T	Reduction (%)	Duration (periods)	Performance Criteria
	0	100	250	C

19.1 BLOCK DIAGRAM OF TEST SETUP



19.2 TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
EUT worked with resistance load, and make sure EUT worked normally.
Setting the parameter of tests and then perform the test software of test simulator.
Conditions changes to occur at 0 degree crossover point of the voltage waveform.
Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum
(Between each test event)

Voltage Dips:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Michelin Performance Criteria
0	100	0.5	Normal	A
0	100	1	Normal	A
70	30	25	Normal.	A

Voltage Interruption:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Michelin Performance Criteria
0	100	250	The EUT stopped working during the test, but it can be recovered automatically after test.	B

19.3. PERFORMANCE

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

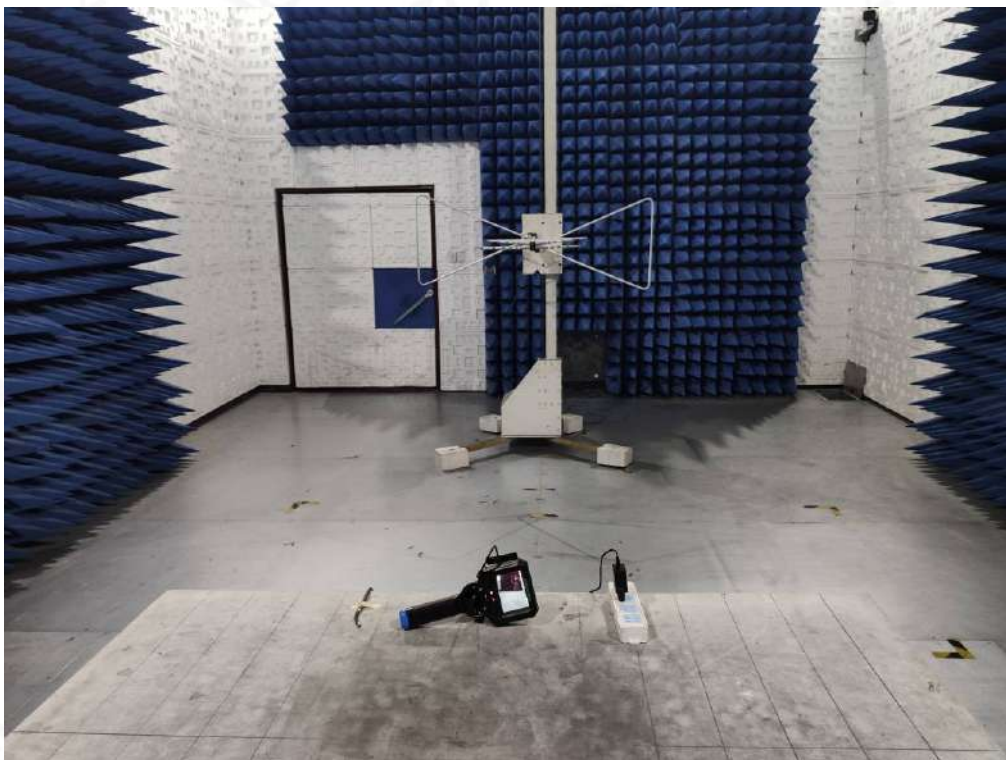
☒ **PASS**
☐ **FAIL**


APPENDIX A: PHOTOGRAPHS OF TEST SETUP

EN 61000-6-3 CONDUCTED EMISSION TEST SETUP



EN 61000-6-3 RADIATED EMISSION TEST SETUP



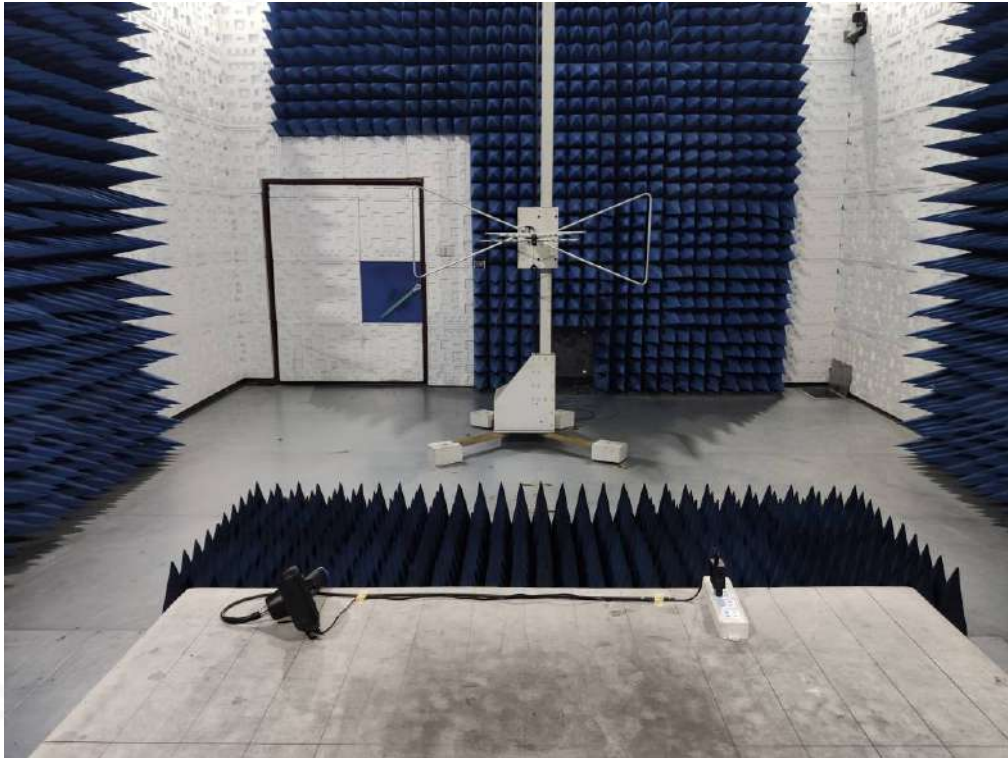
EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST SETUP



EN 61000-4-2 ESD IMMUNITY TEST SETUP



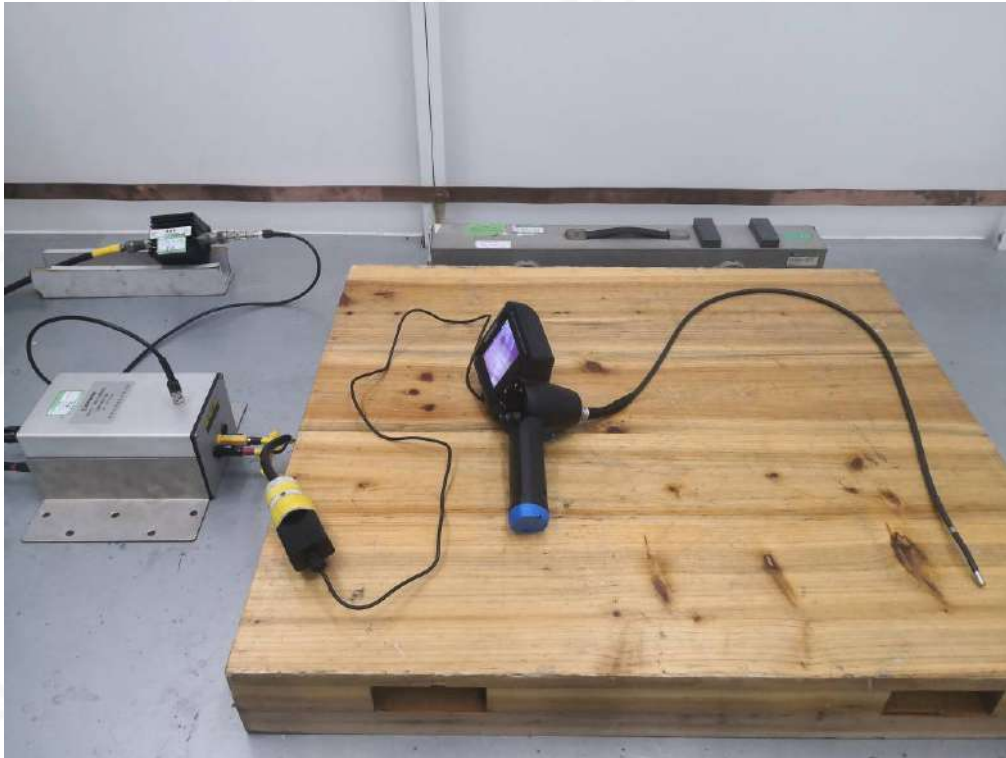
EN 61000-4-3 RS IMMUNITY TEST SETUP



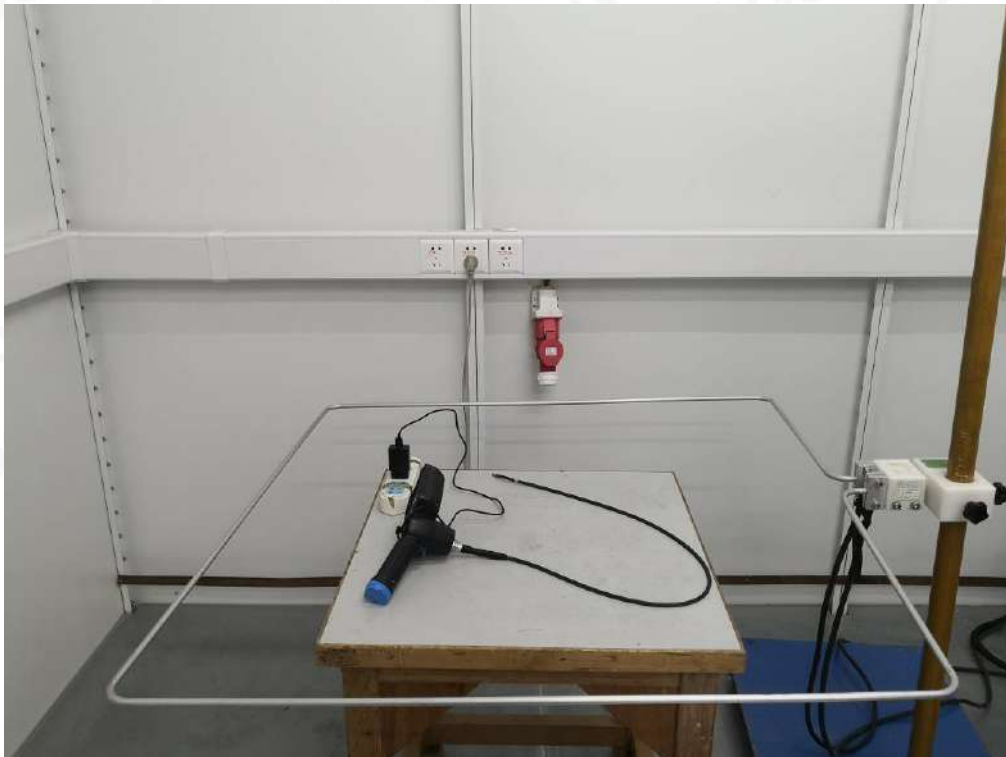
EN 61000-4-4/5/11 EFT/ SURGE/ DIPS IMMUNITY TEST SETUP



EN 61000-4-6 CS IMMUNITY TEST SETUP



EN 61000-4-8 PFMF TEST SETUP



APPENDIX B: PHOTOGRAPHS OF EUT

ALL VIEW OF EUT-1



ALL VIEW OF EUT-2



ADAPTER VIEW OF EUT



TOP VIEW OF EUT



BOTTOM VIEW OF EUT



FRONT VIEW OF EUT



BACK VIEW OF EUT



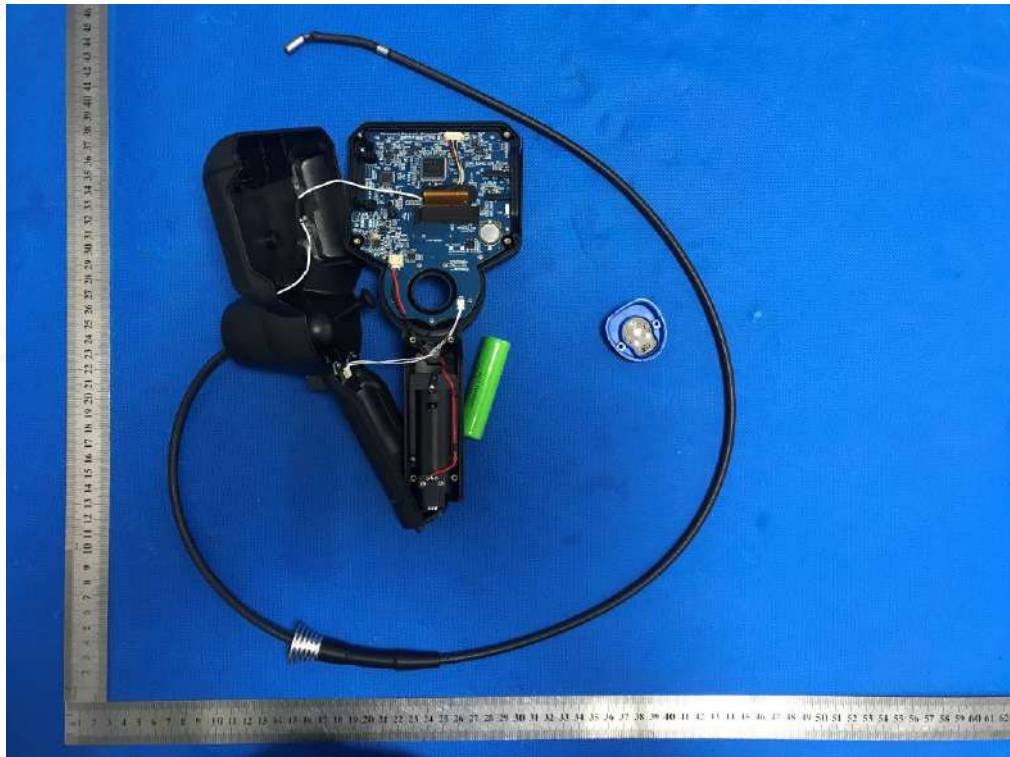
LEFT VIEW OF EUT



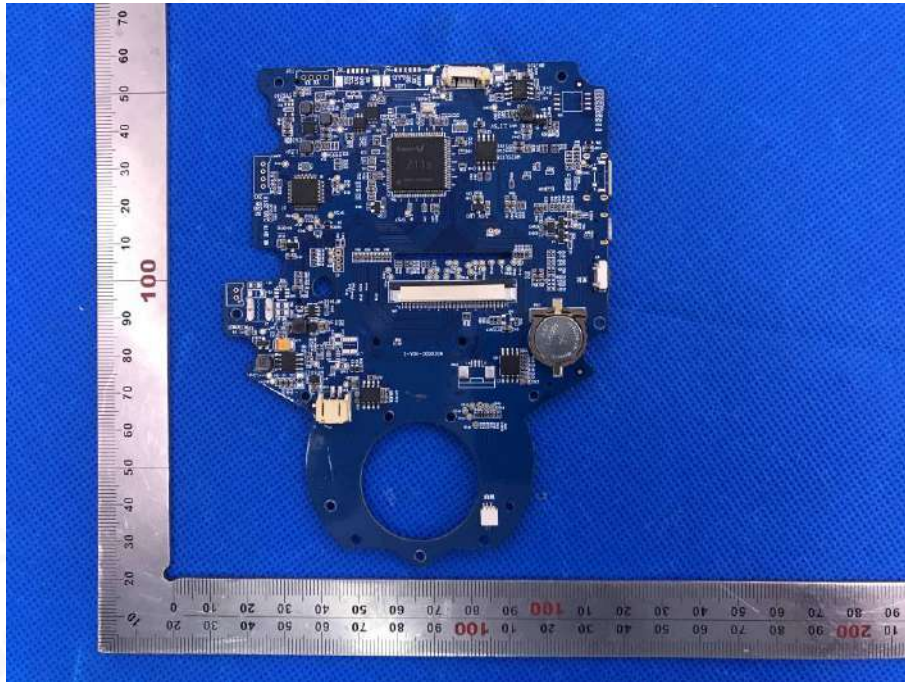
RIGHT VIEW OF EUT



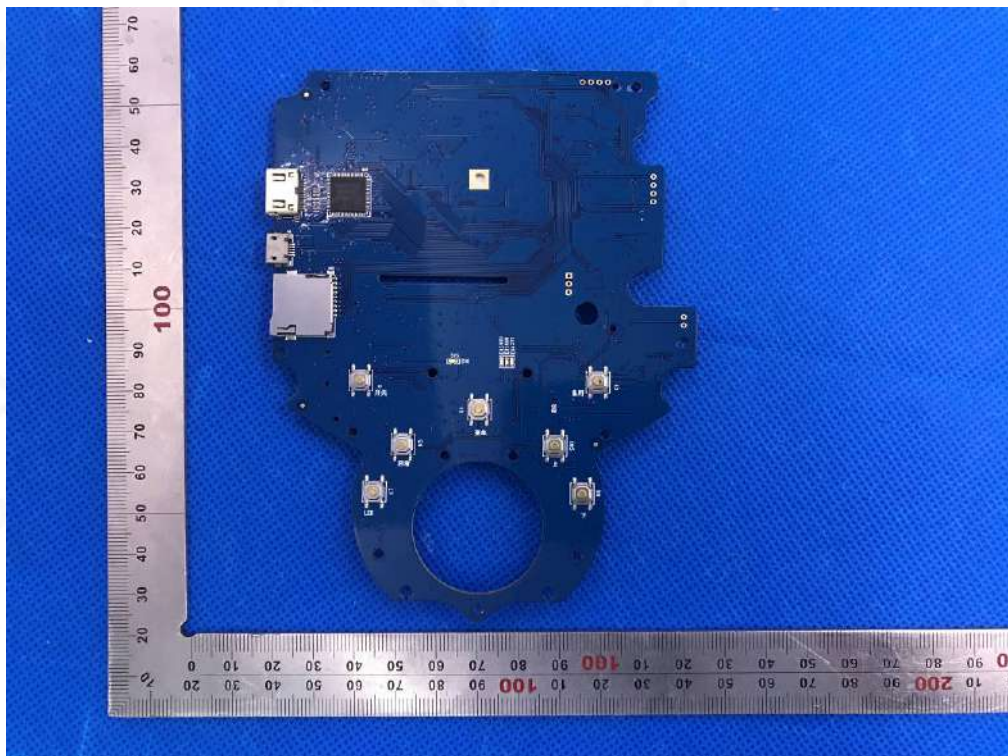
OPEN VIEW OF EUT



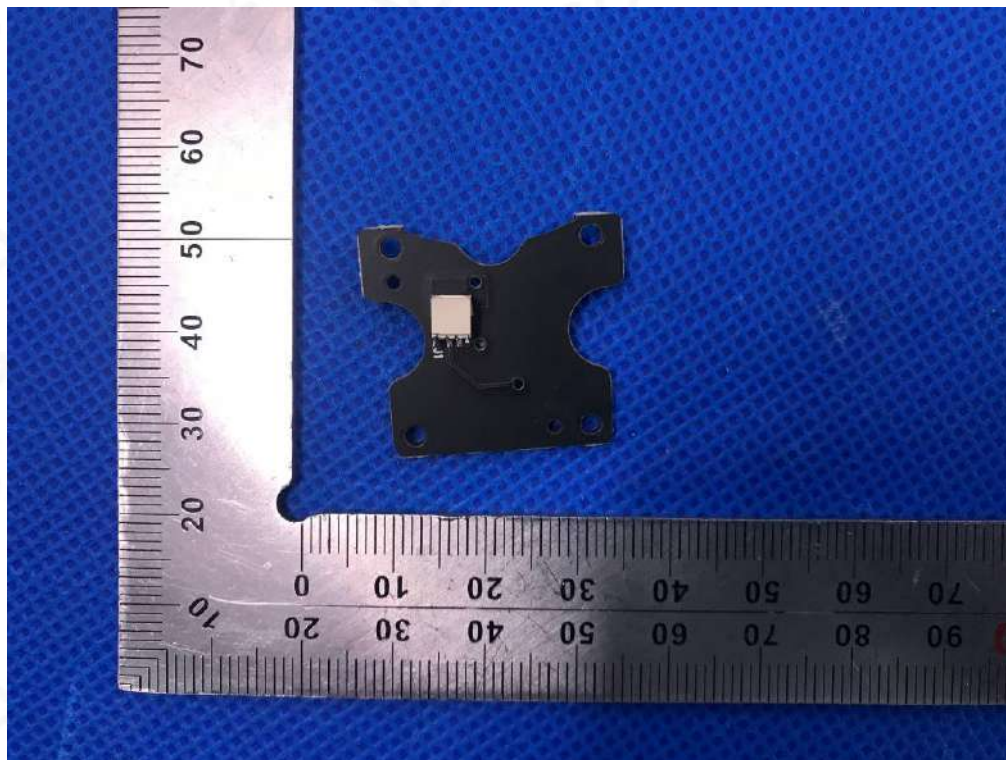
INTERNAL VIEW OF EUT-1



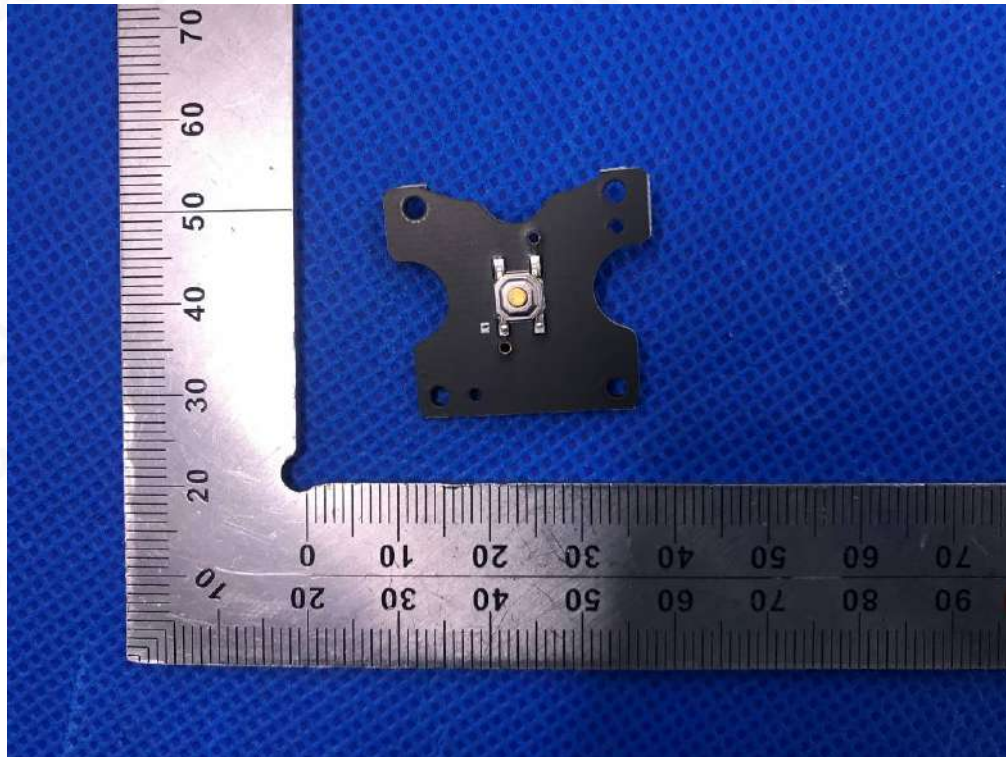
INTERNAL VIEW OF EUT-2



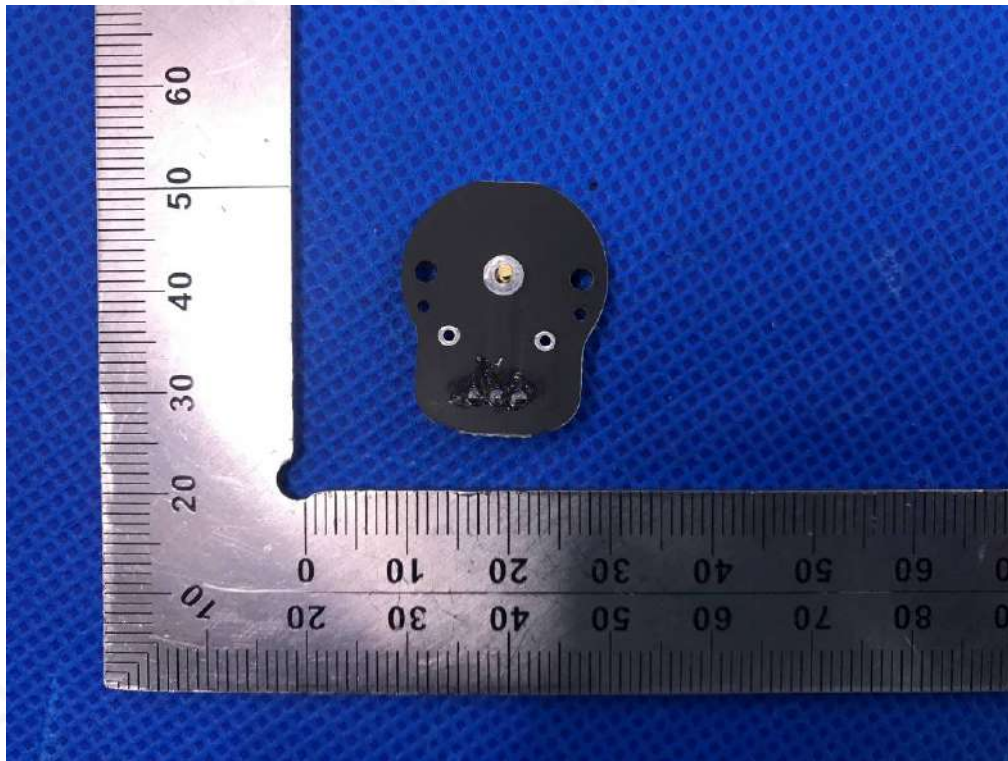
INTERNAL VIEW OF EUT-3



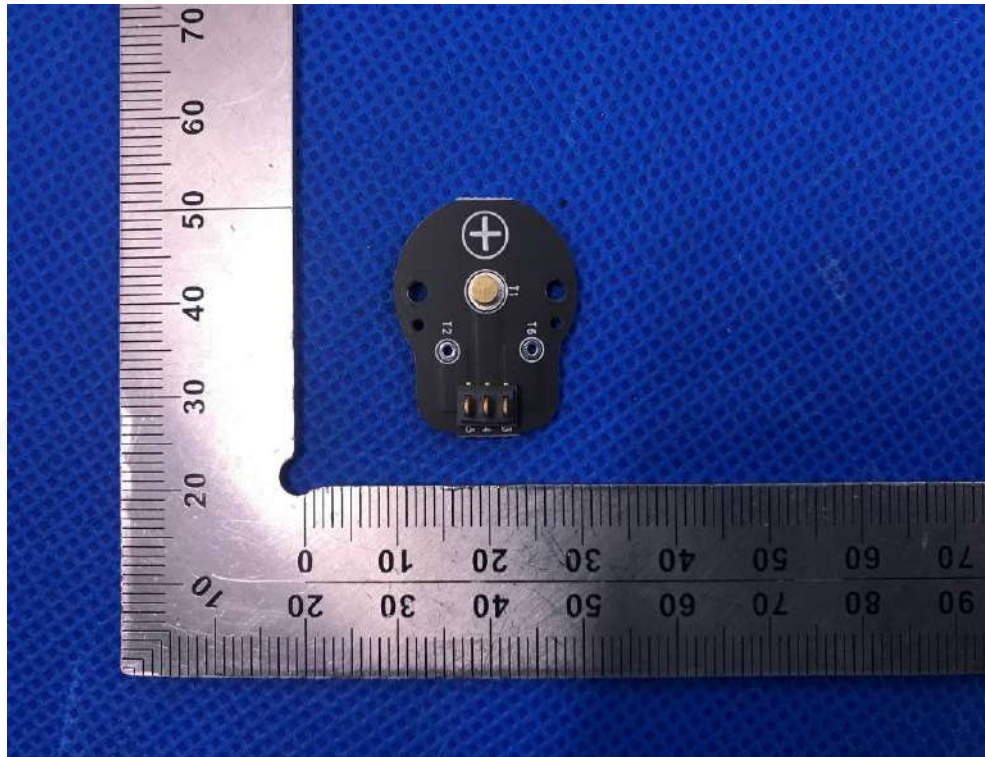
INTERNAL VIEW OF EUT-4



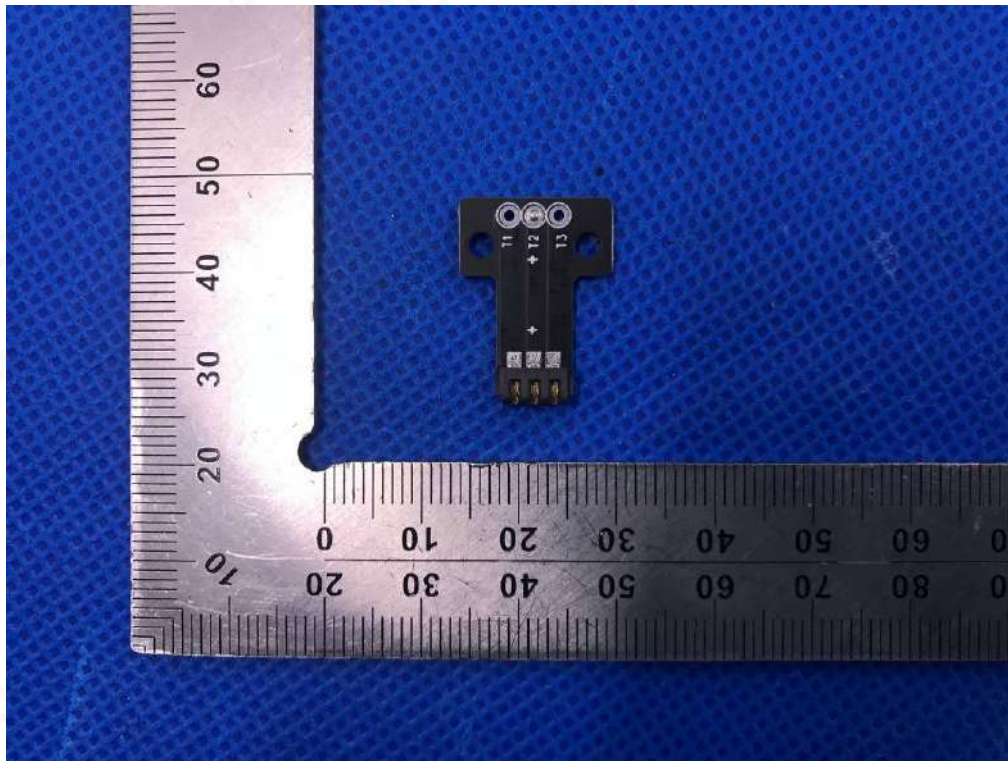
INTERNAL VIEW OF EUT-5



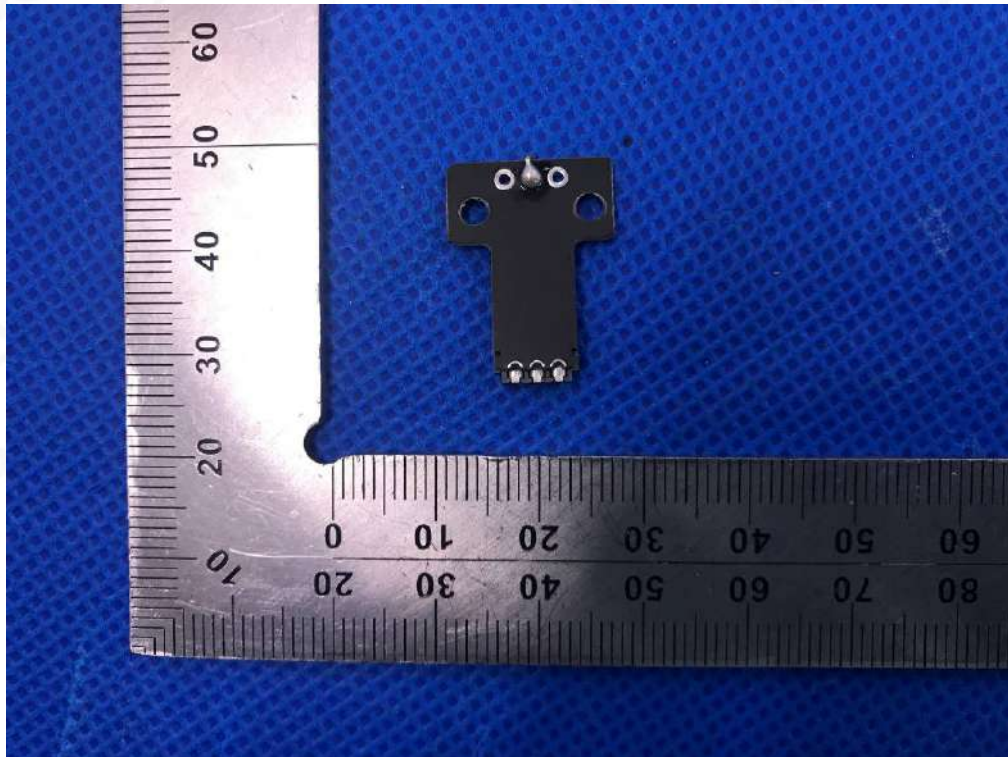
INTERNAL VIEW OF EUT-6



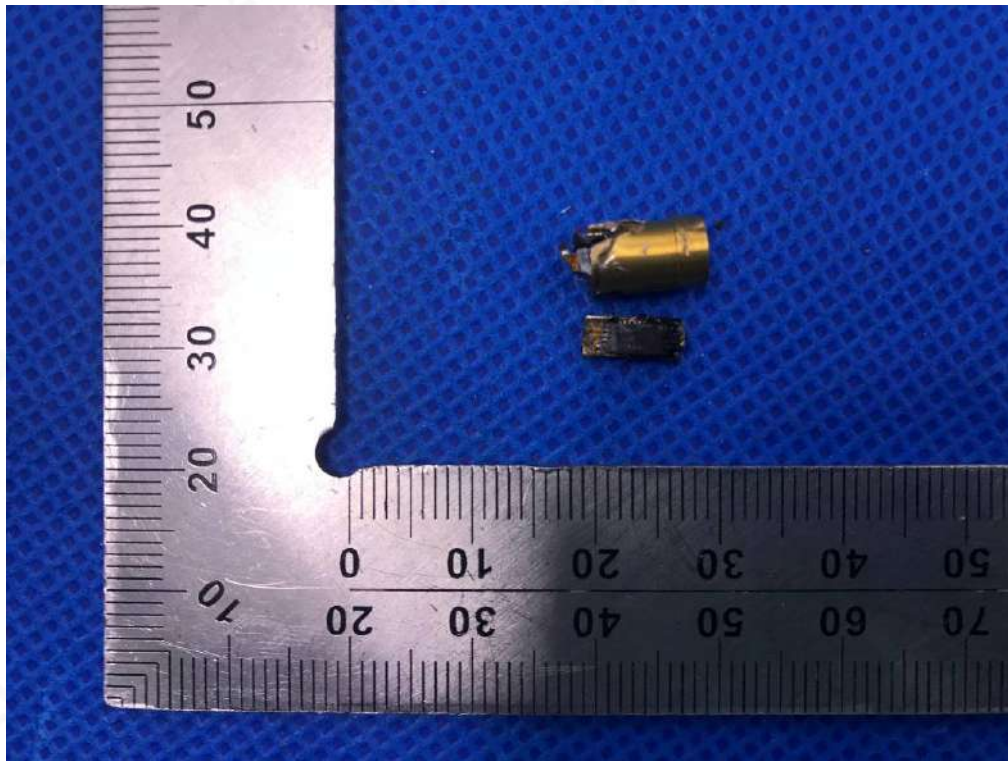
INTERNAL VIEW OF EUT-7



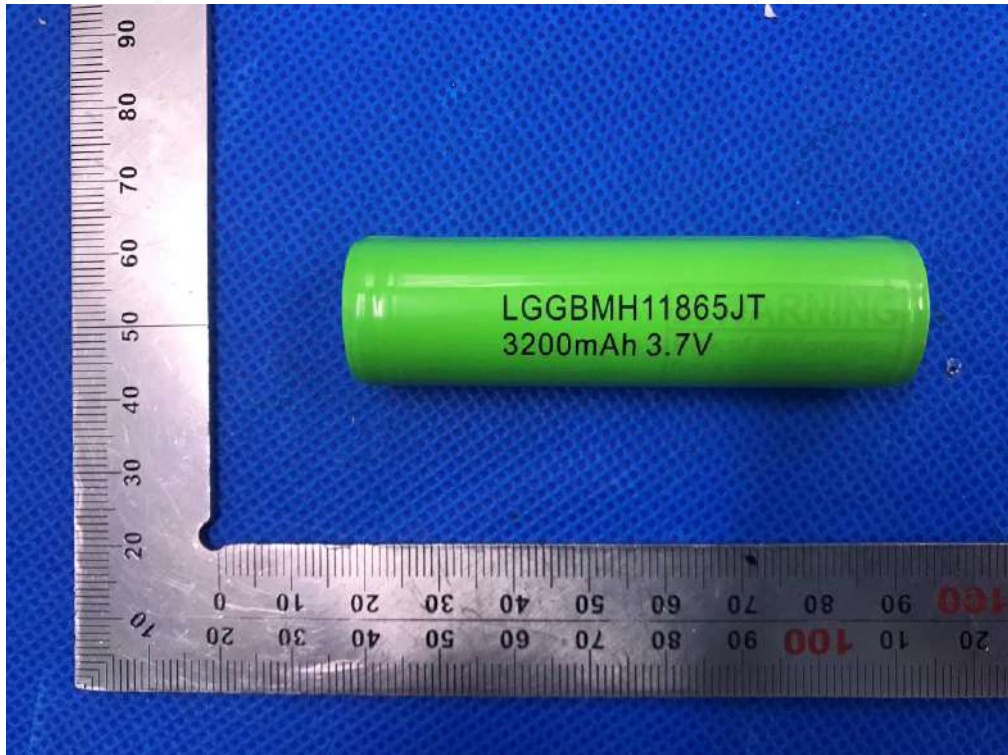
INTERNAL VIEW OF EUT-8



INTERNAL VIEW OF EUT-9



BATTERY VIEW OF EUT



----END OF REPORT----